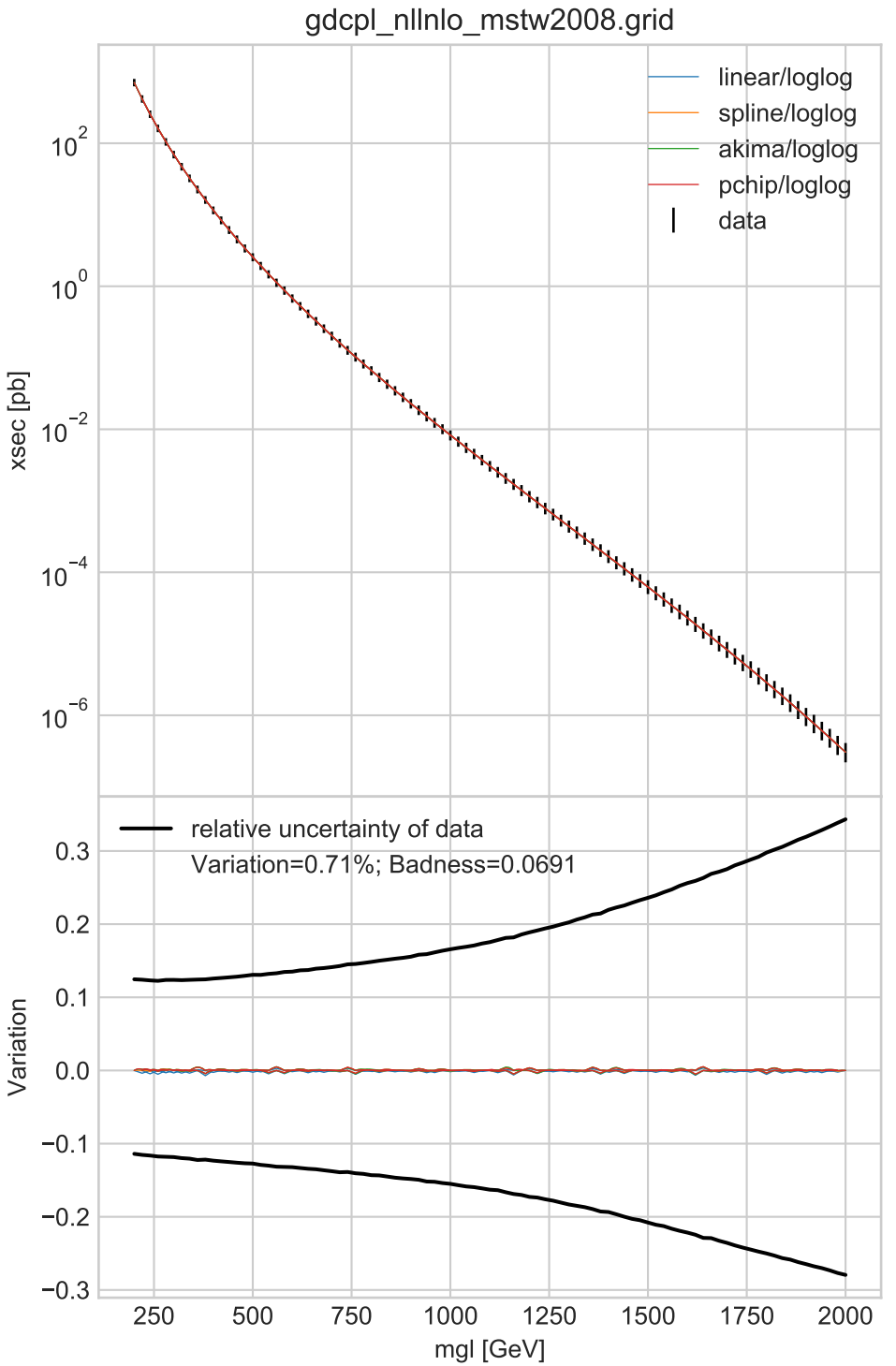
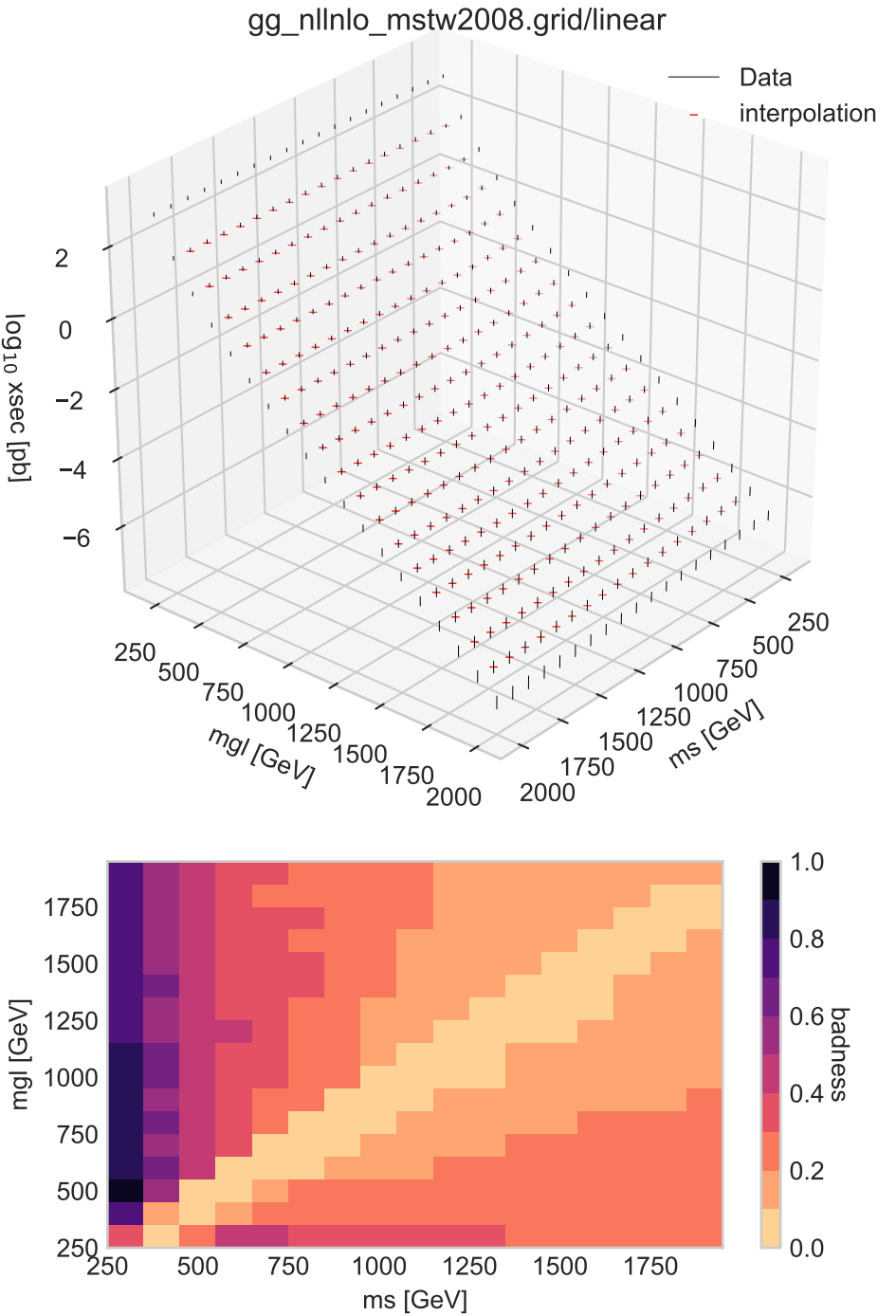
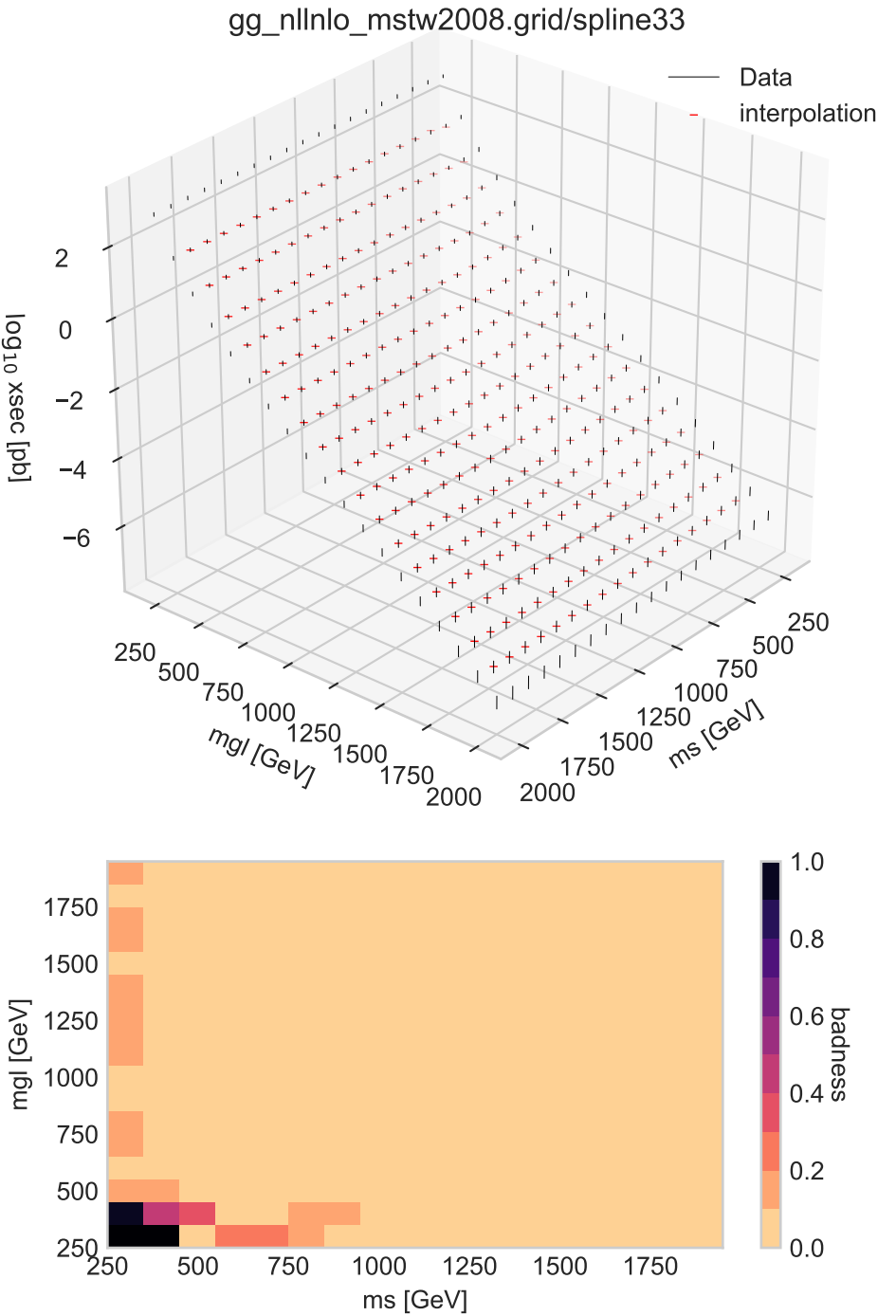
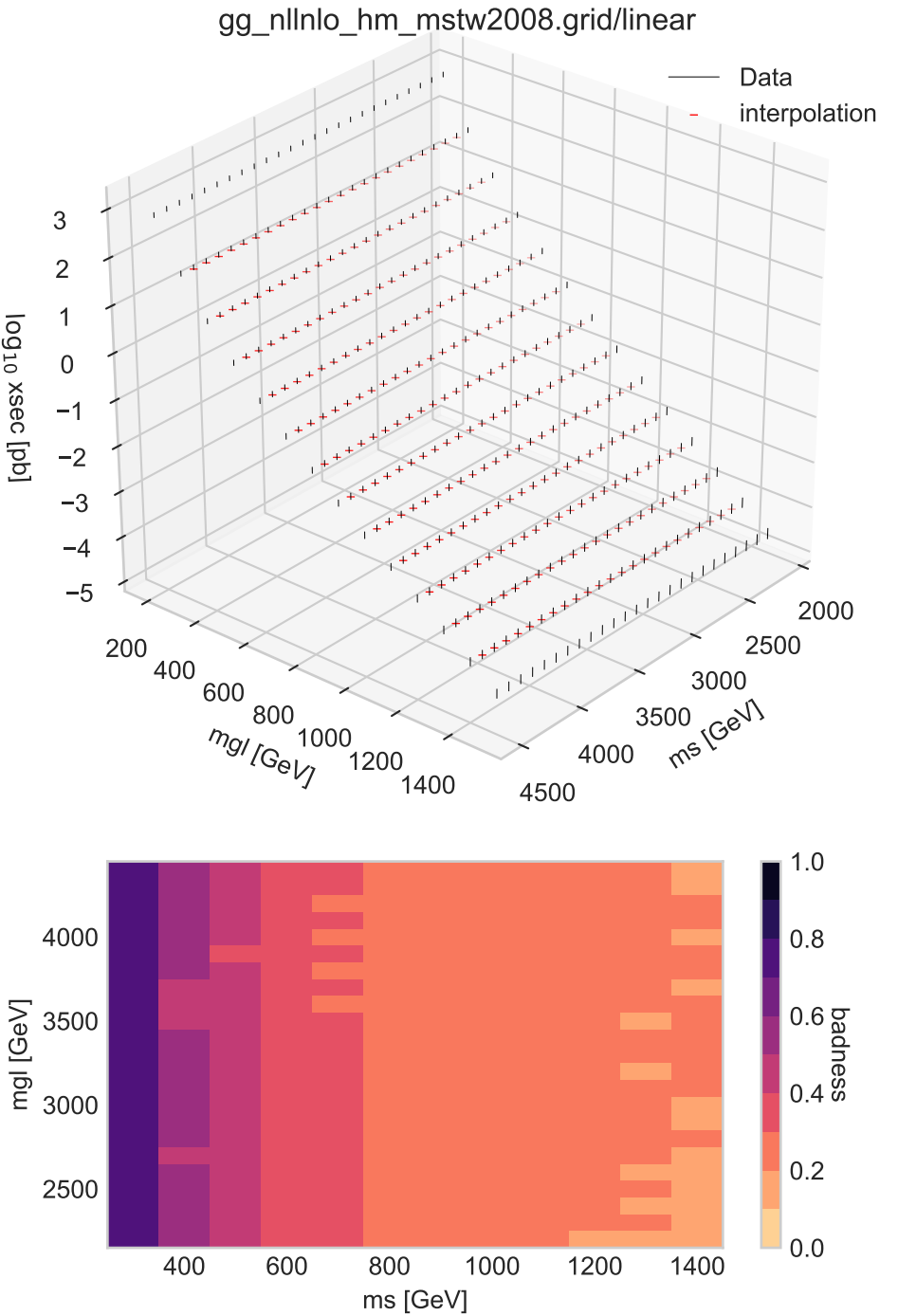
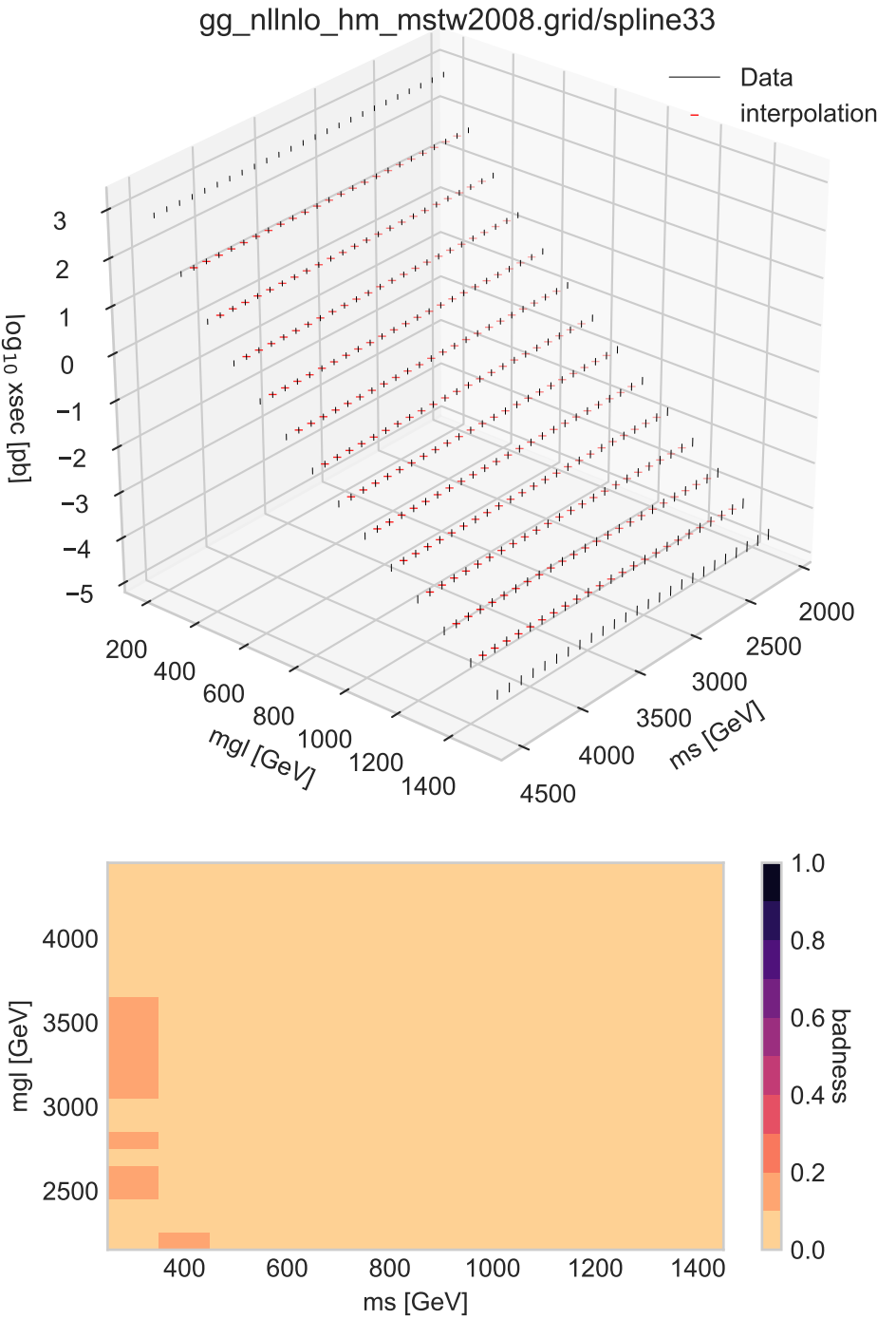
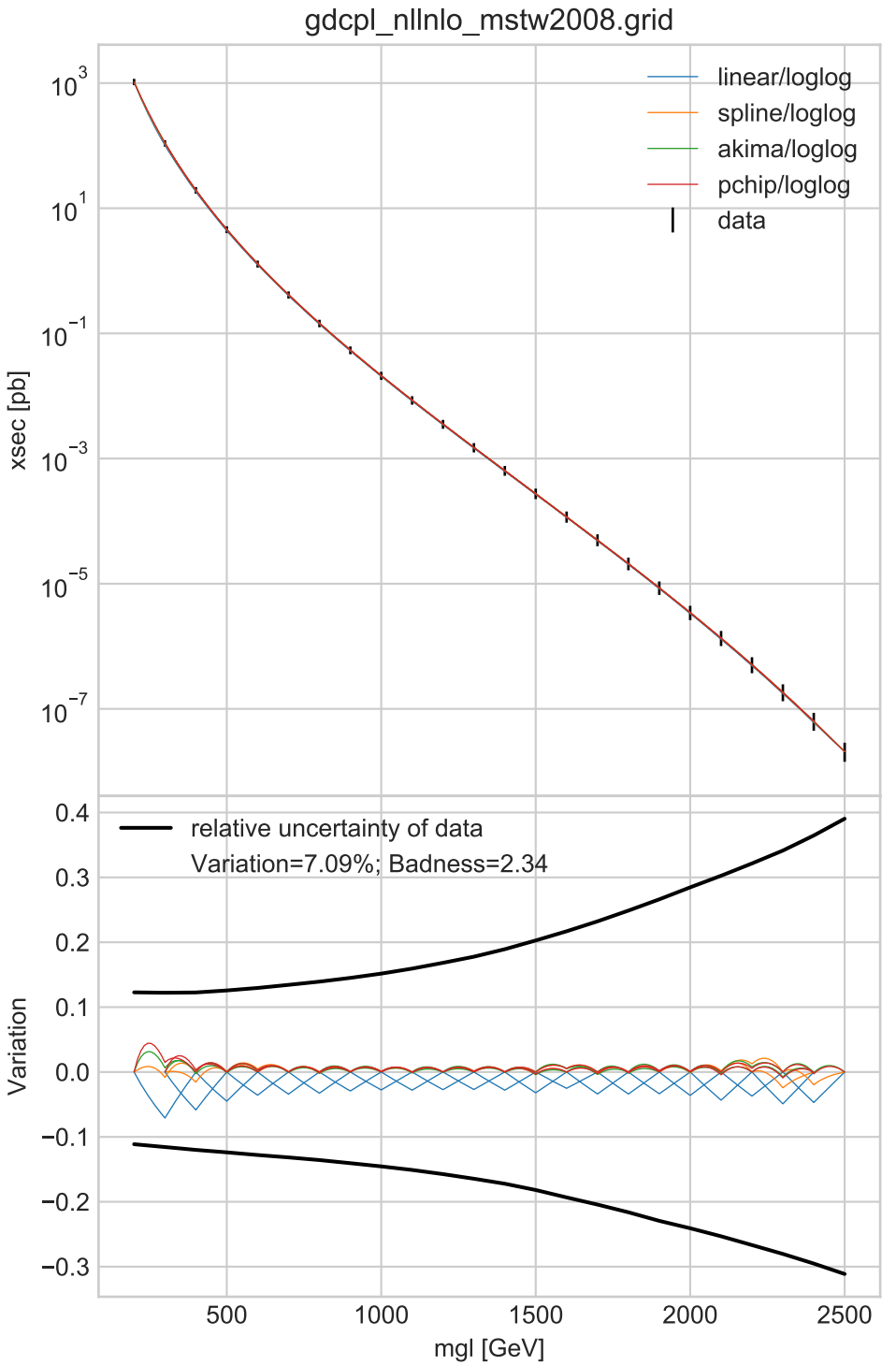

gdcpl_nllnlo_mstw2008.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
10^{2}
10^{0}
10^{-2}
10^{-4}
10^{-6}
relative uncertainty of data
Variation=0.71%; Badness=0.0691
Variation
0.3
0.2
0.1
0.0
−0.1
−0.2
−0.3
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]

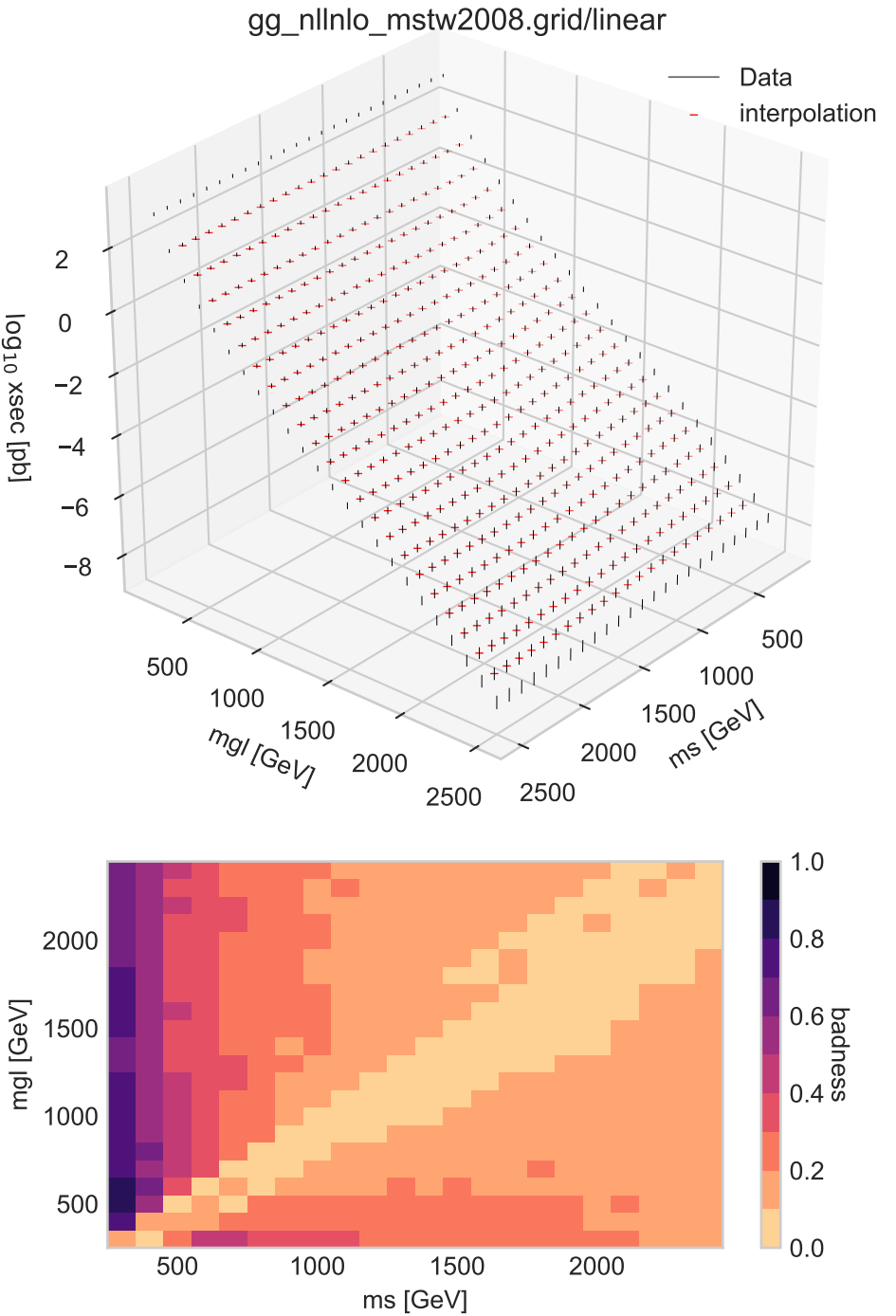

gg_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

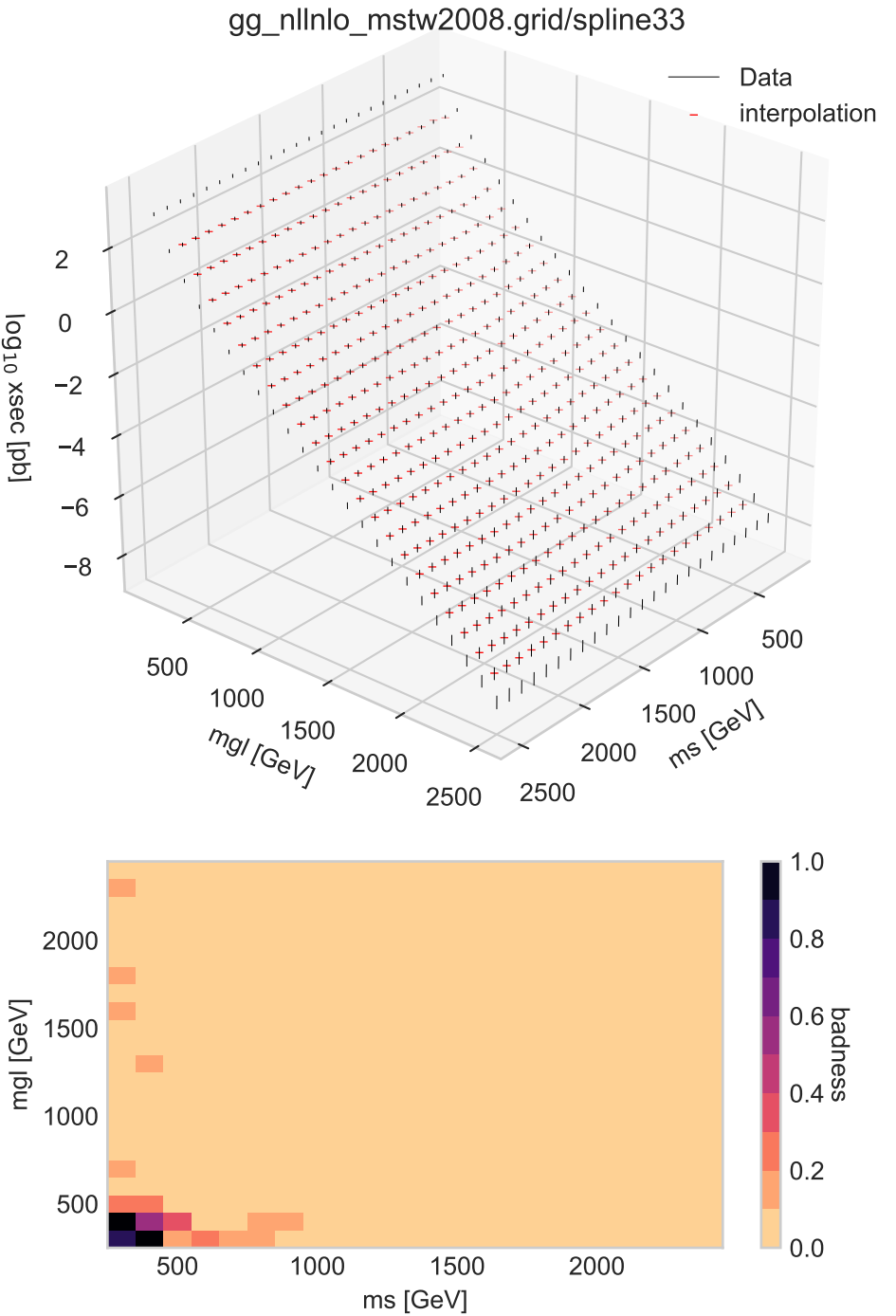

gg_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
badness
0.0
0.2
0.4
0.6
0.8
1.0

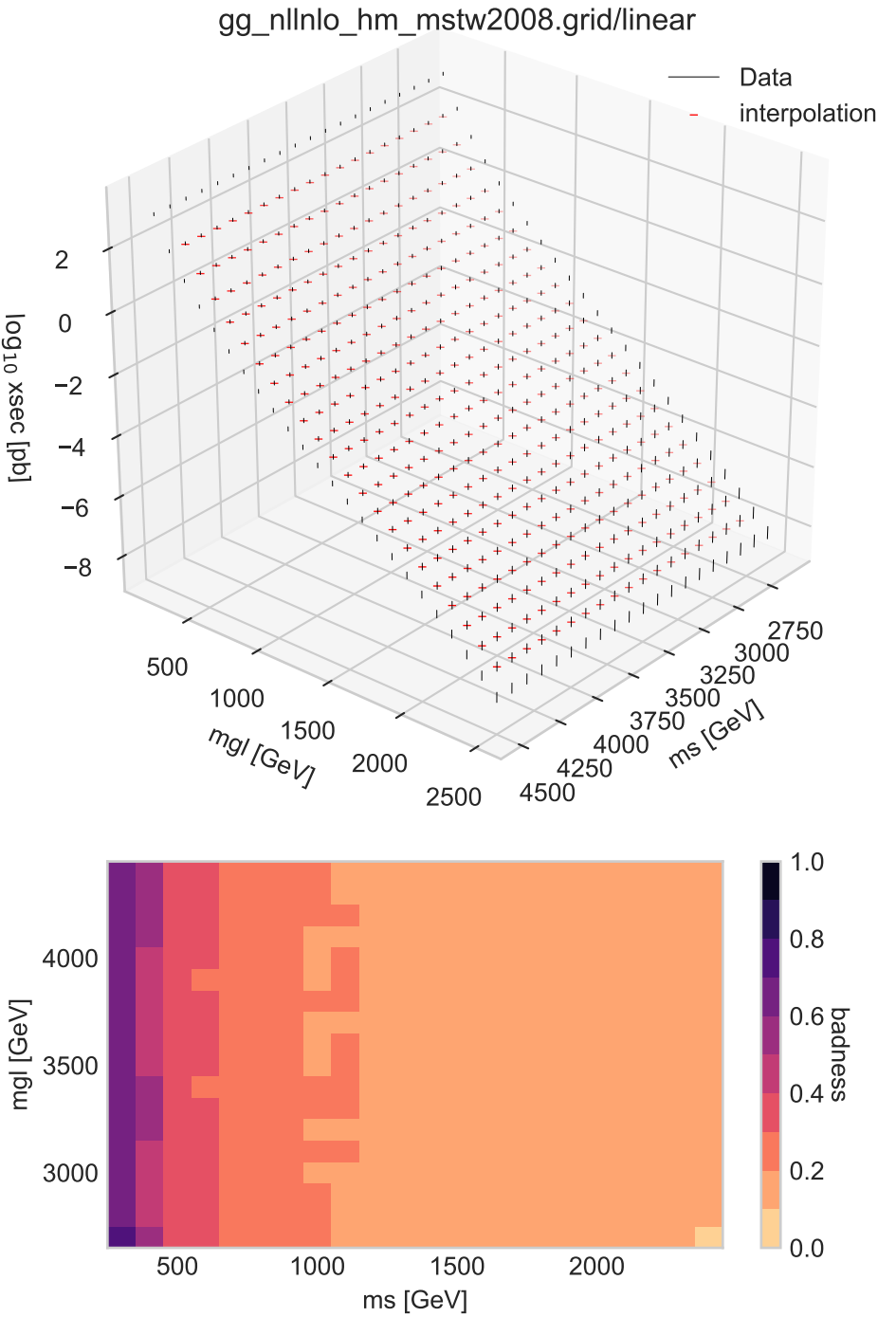

gg_nllnlo_hm_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
3
2
1
0
−1
−2
−3
−4
−5
200
400
600
800
1000
1200
1400
mgl [GeV]
2000
2500
3000
3500
4000
4500
ms [GeV]
mgl [GeV]
4000
3500
3000
2500
400
600
800
1000
1200
1400
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

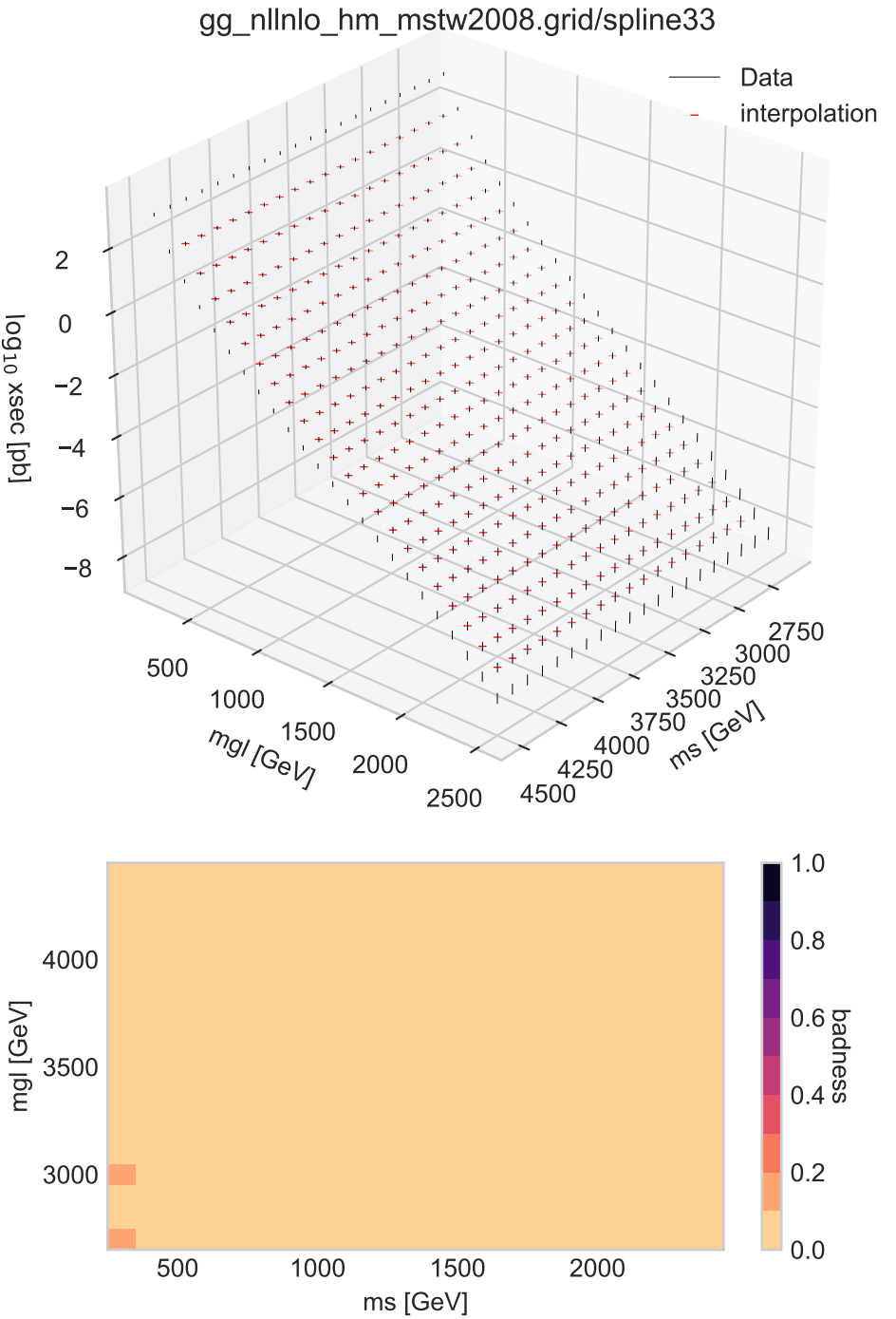

gg_nllnlo_hm_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
3
2
1
0
−1
−2
−3
−4
−5
200
400
600
800
1000
1200
1400
mgl [GeV]
2000
2500
3000
3500
4000
4500
ms [GeV]
mgl [GeV]
4000
3500
3000
2500
400
600
800
1000
1200
1400
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

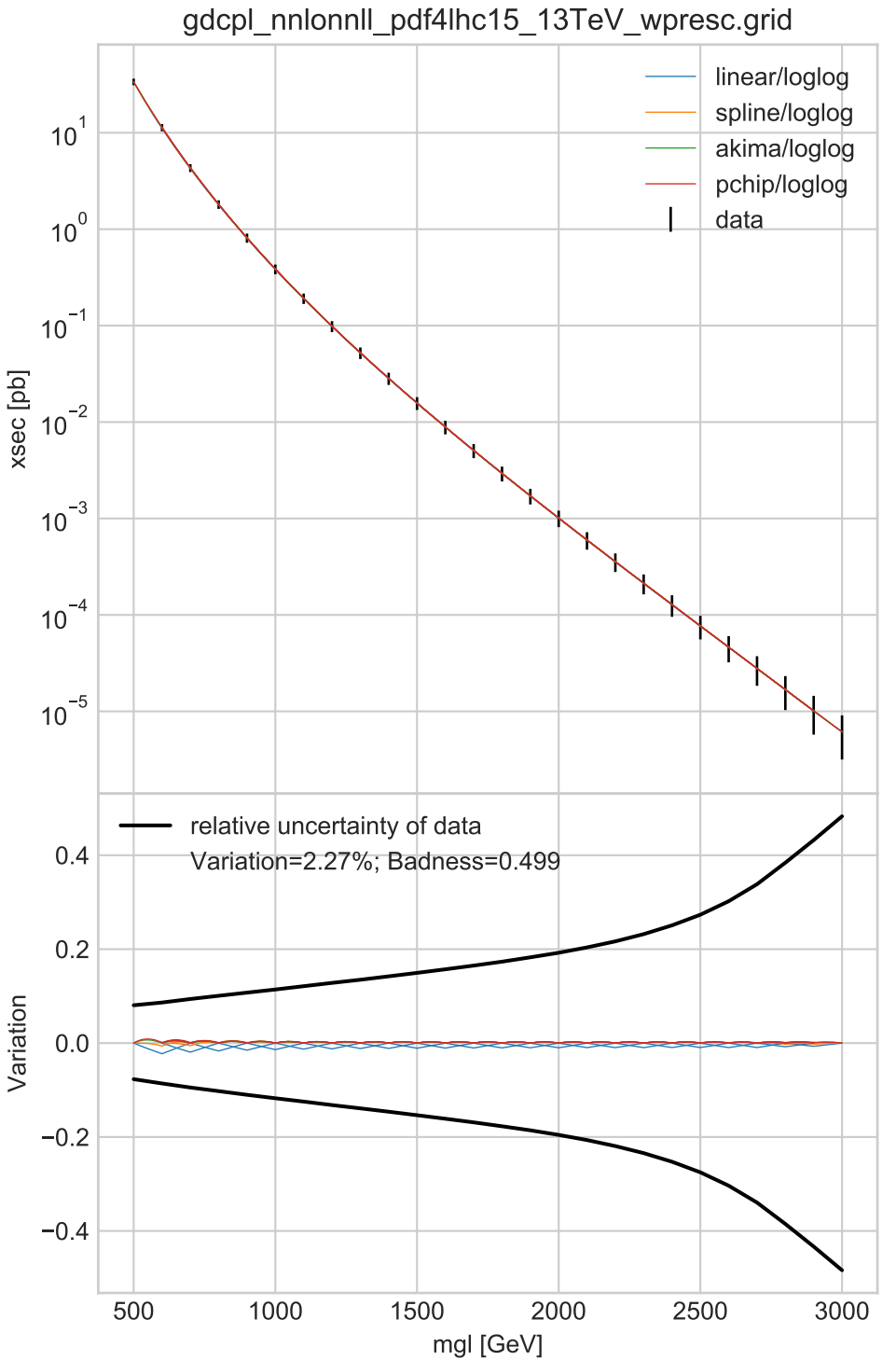

gdcpl_nllnlo_mstw2008.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
relative uncertainty of data
Variation=7.09%; Badness=2.34
Variation
mgl [GeV]

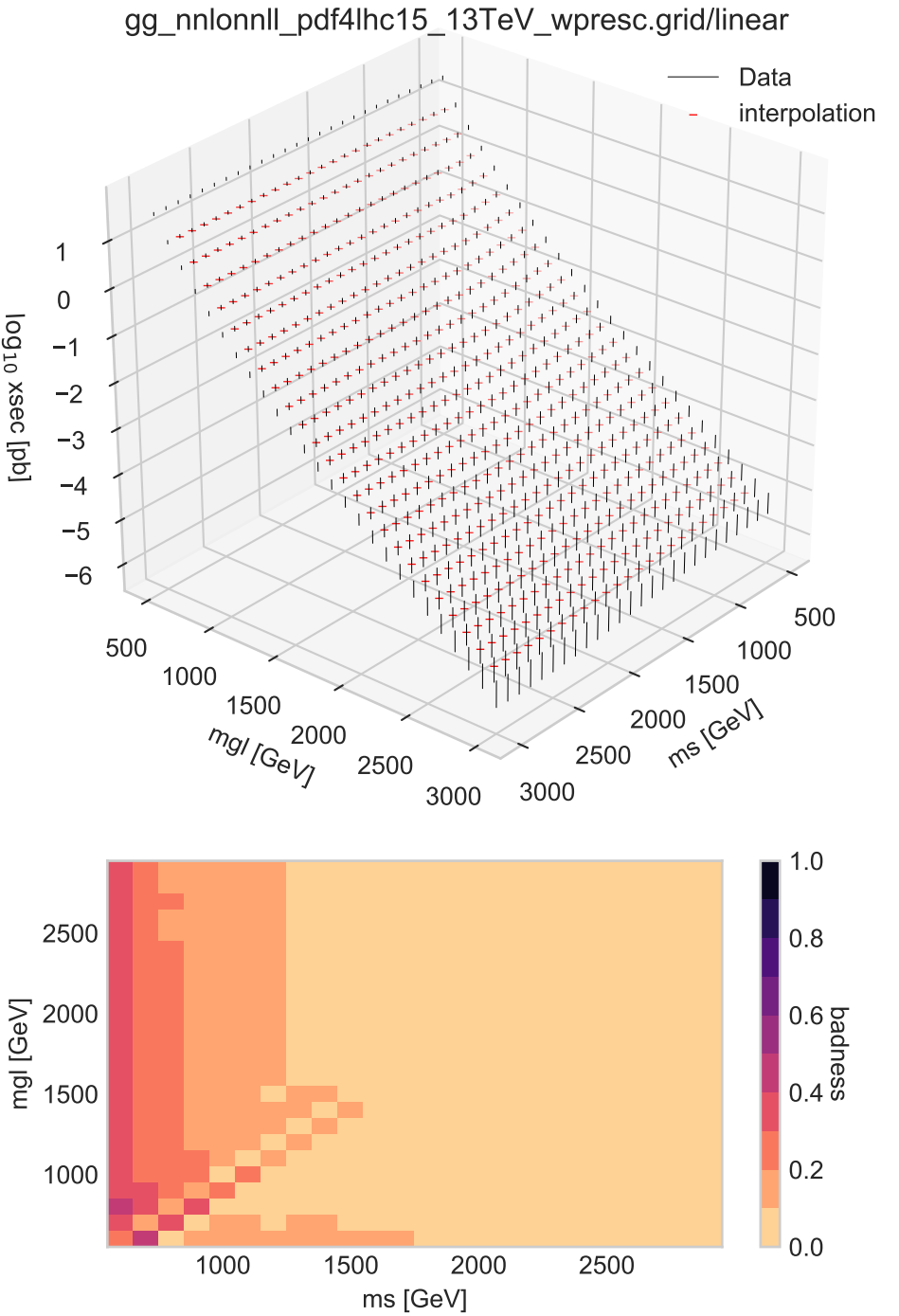

gg_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
500
1000
1500
2000
2500
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

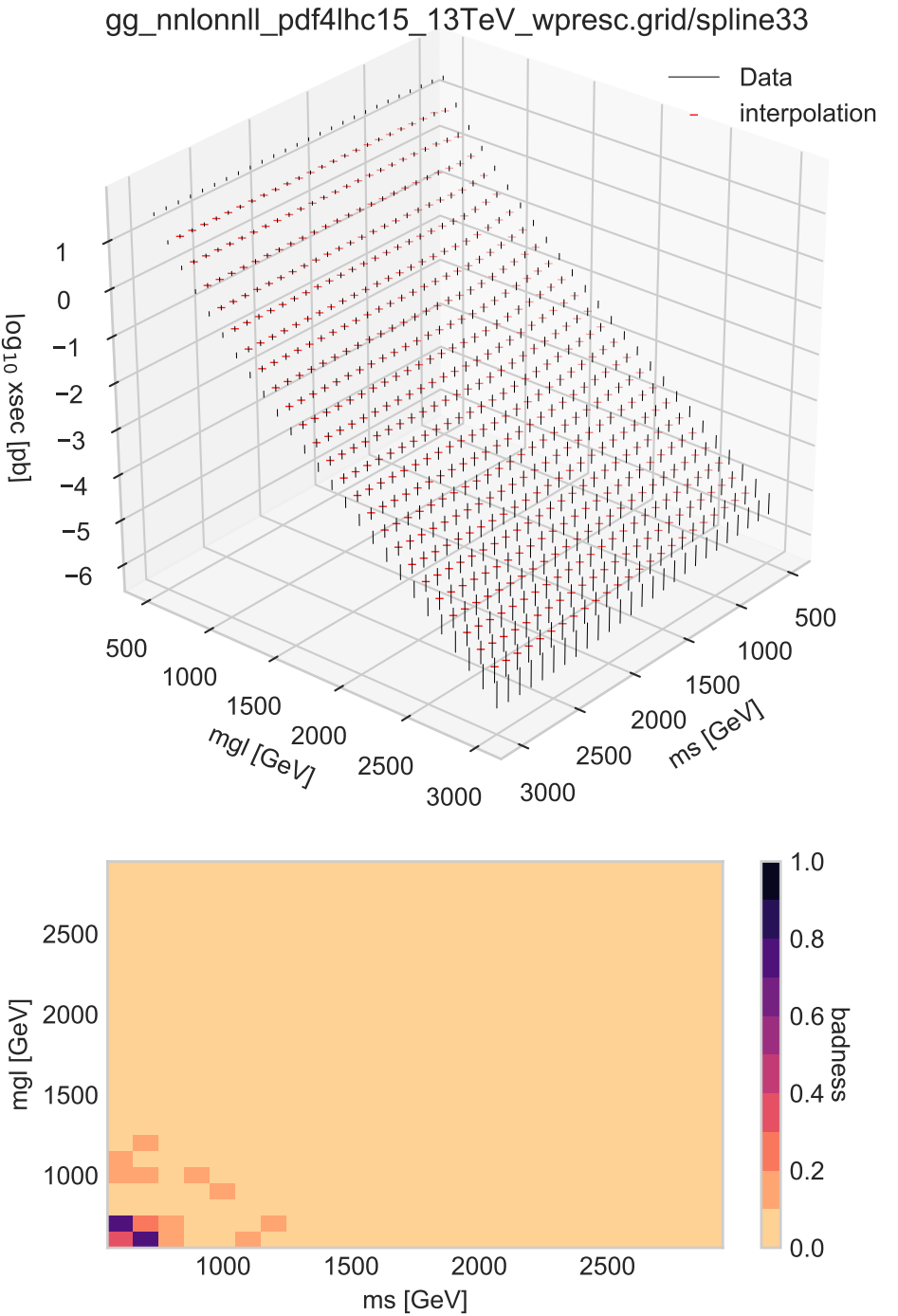

gg_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
mgl [GeV]
ms [GeV]
500
1000
1500
2000
2500
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

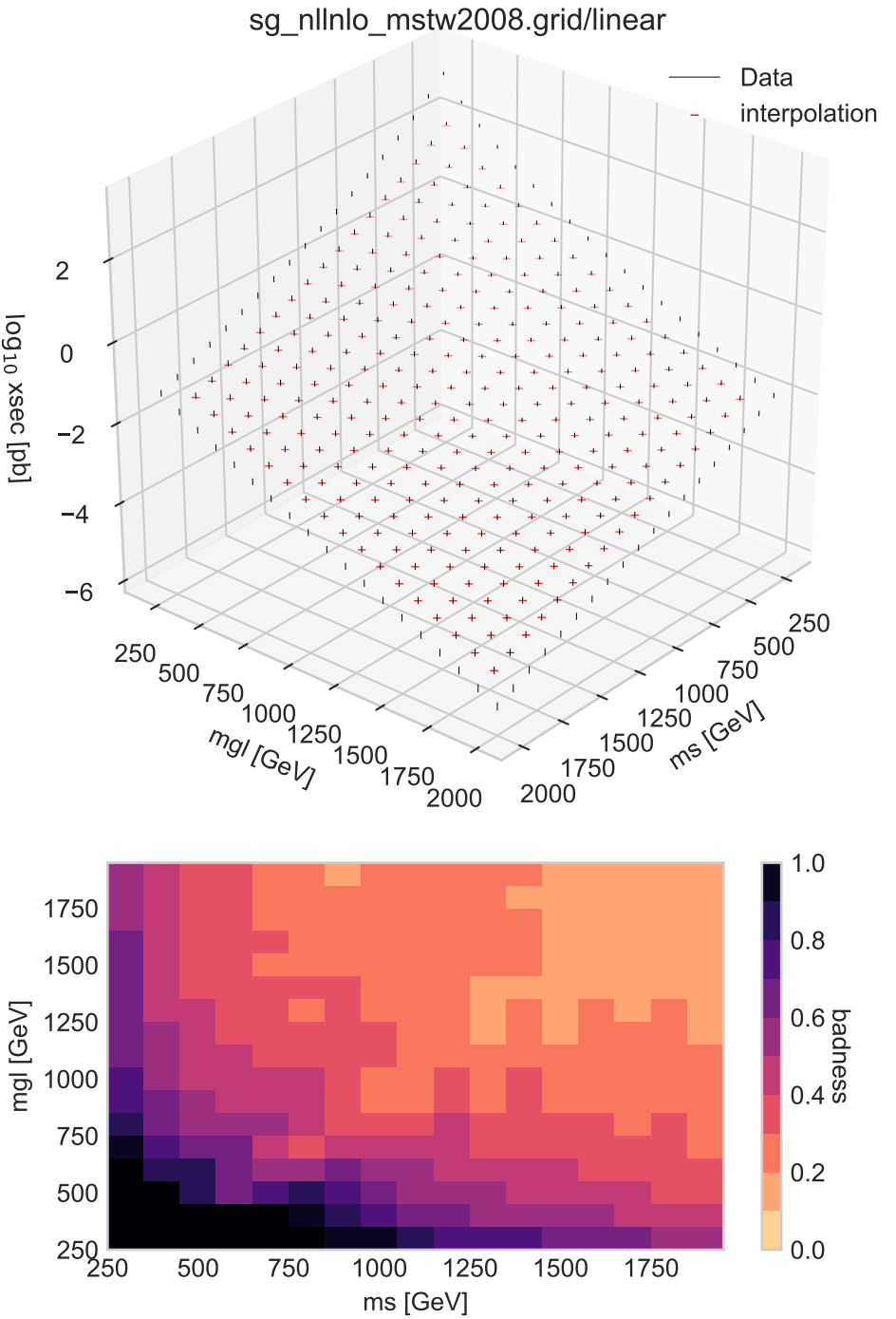

gg_nllnlo_hm_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
500
1000
1500
2000
2500
mgl [GeV]
2750
3000
3250
3500
3750
4000
4250
4500
ms [GeV]
mgl [GeV]
4000
3500
3000
500
1000
1500
2000
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

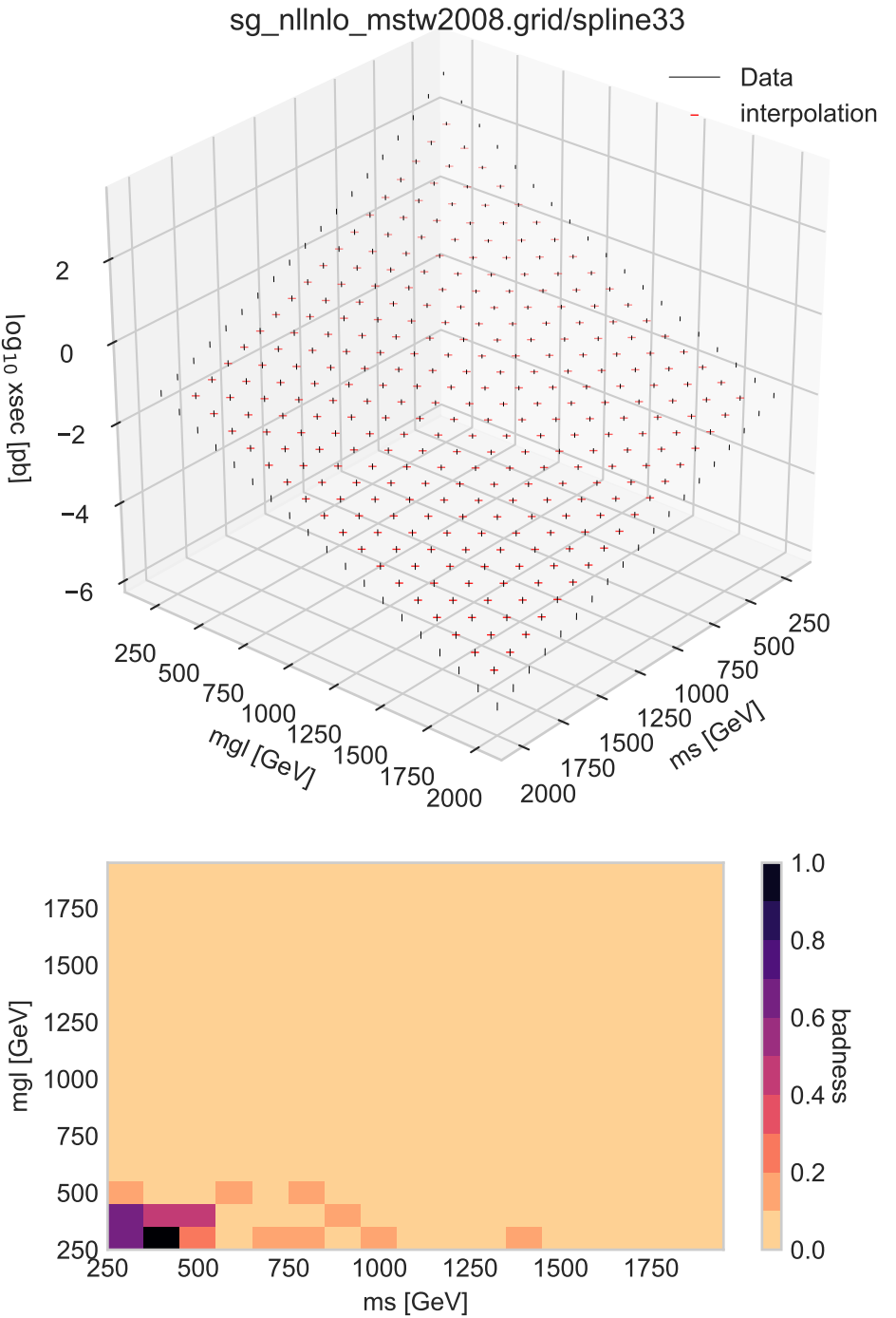

gg_nllnlo_hm_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
mgl [GeV]
500
1000
1500
2000
2500
ms [GeV]
2750
3000
3250
3500
3750
4000
4250
4500
mgl [GeV]
4000
3500
3000
ms [GeV]
500
1000
1500
2000
badness
1.0
0.8
0.6
0.4
0.2
0.0

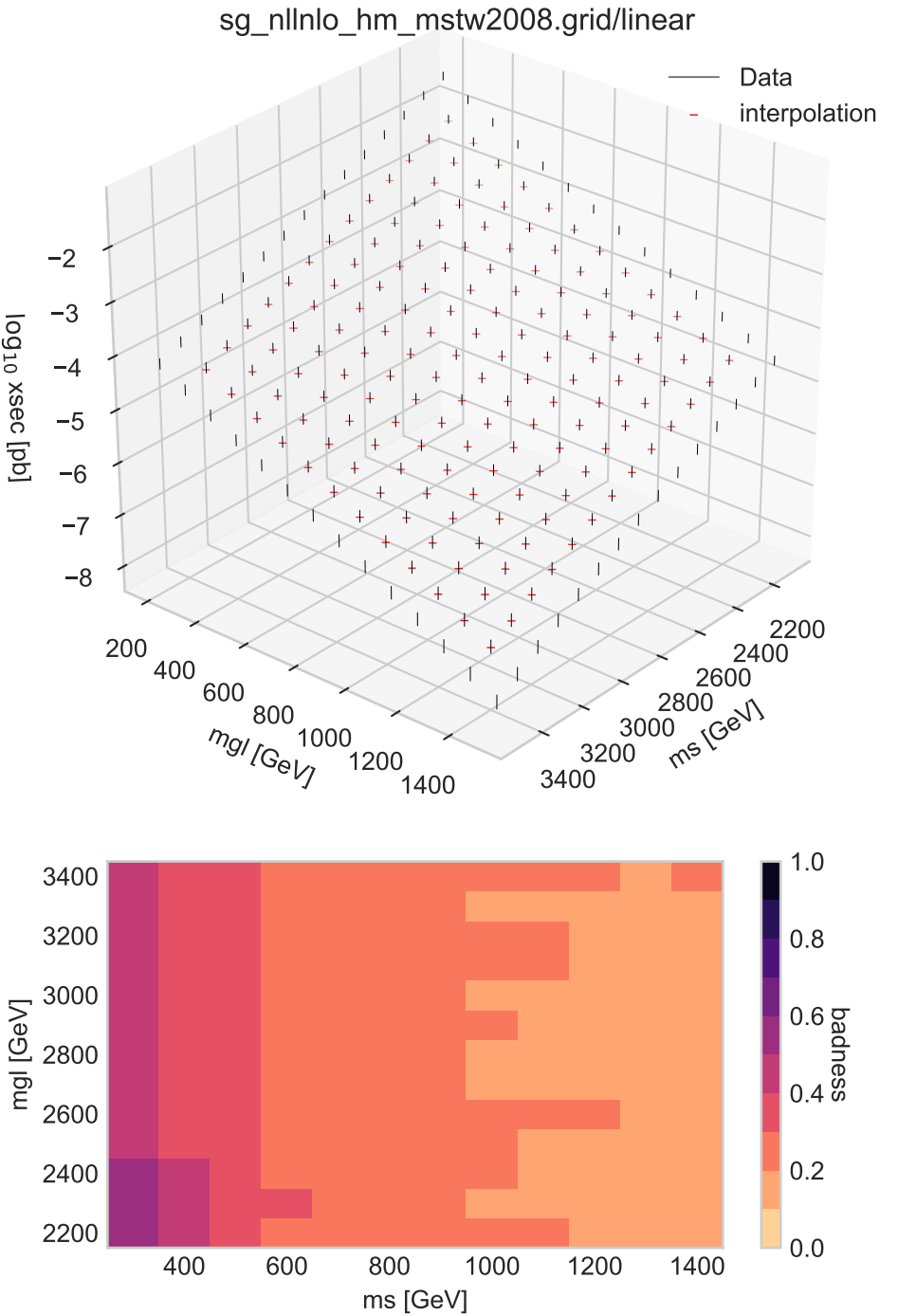

gdcpl_nnlonnll_pdf4lhc15_13TeV_wpresc.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
relative uncertainty of data
Variation=2.27%; Badness=0.499
Variation
mgl [GeV]

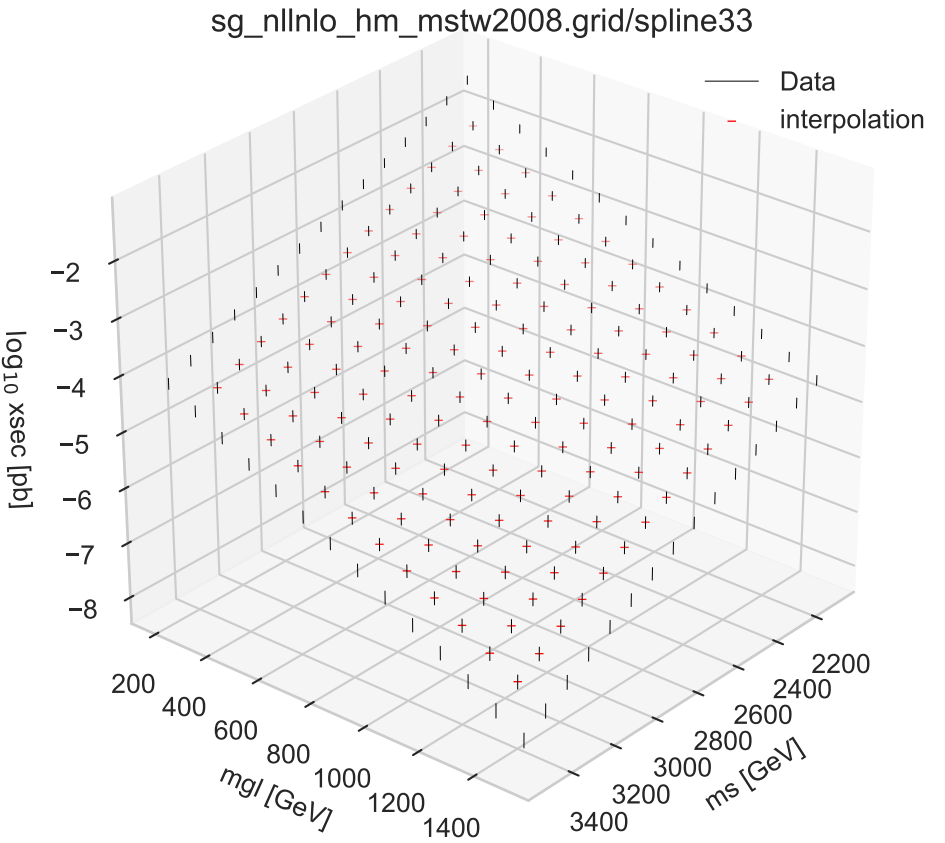

gg_nnlonnll_pdf4lhc15_13TeV_wpresc.grid/linear
Data
interpolation
log10 xsec [pb]
1
0
−1
−2
−3
−4
−5
−6
500
1000
1500
2000
2500
3000
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

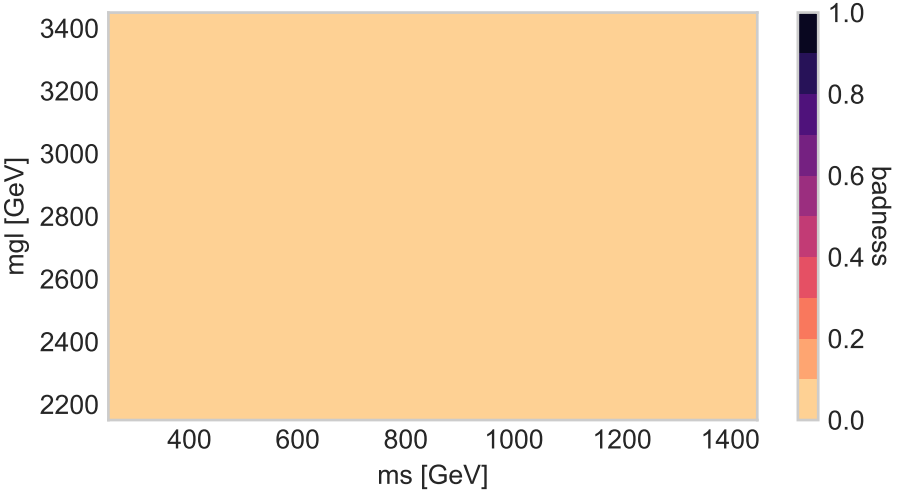

gg_nnlonnll_pdf4lhc15_13TeV_wpresc.grid/spline33
Data
interpolation
log10 xsec [pb]
1
0
−1
−2
−3
−4
−5
−6
500
1000
1500
2000
2500
3000
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

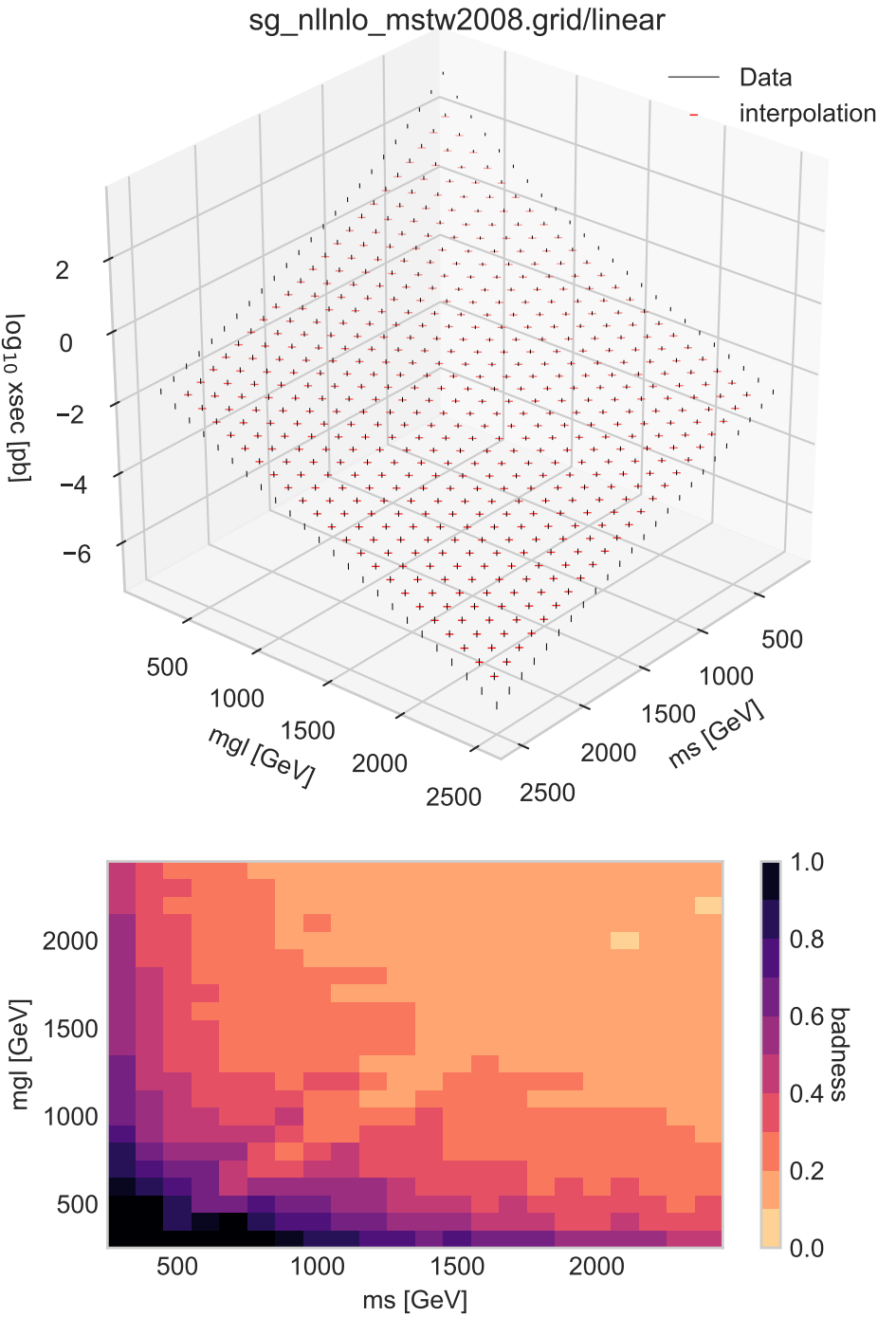

sg_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
250
500
750
1000
1250
1500
1750
2000
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

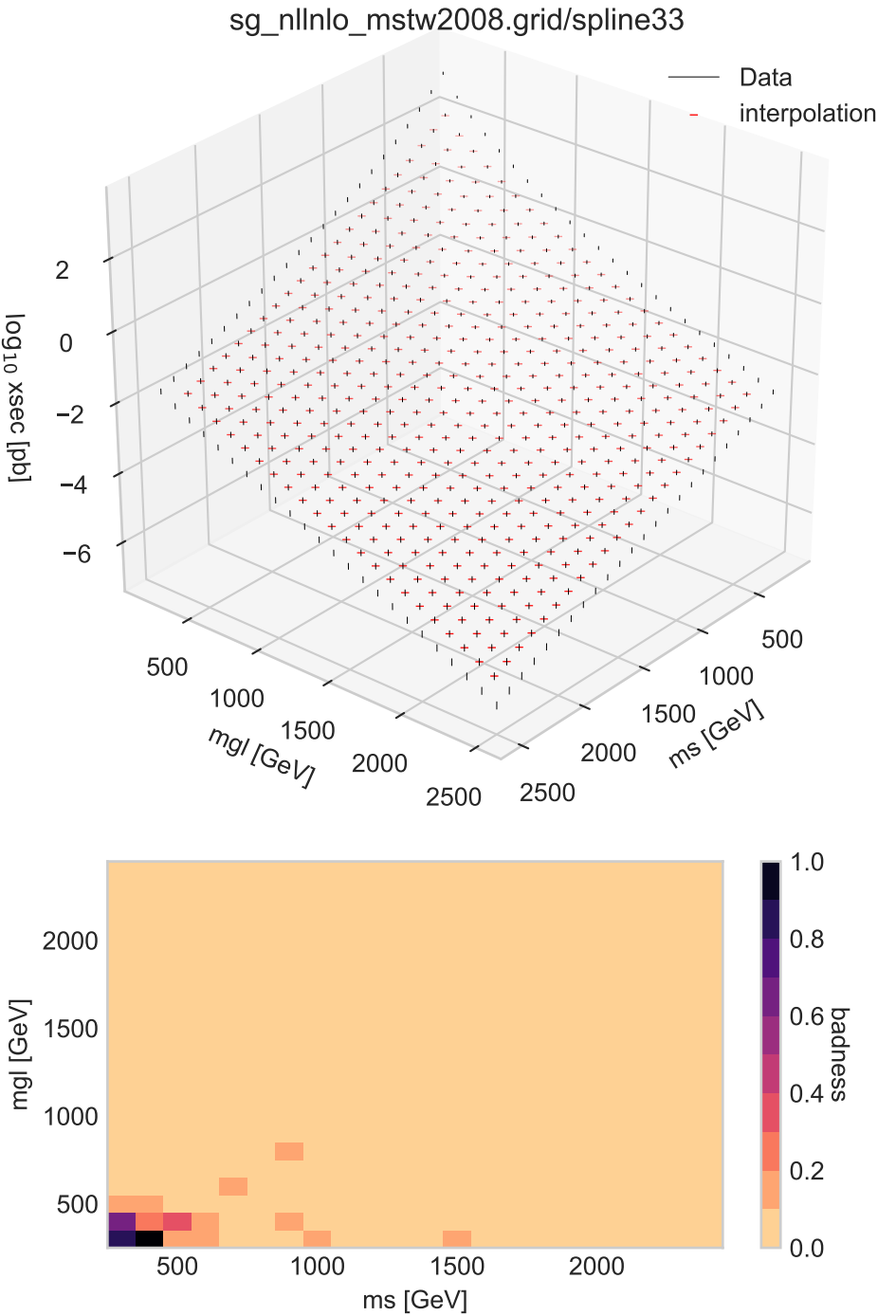

sg_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
250
500
750
1000
1250
1500
1750
2000
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
badness
0.0
0.2
0.4
0.6
0.8
1.0

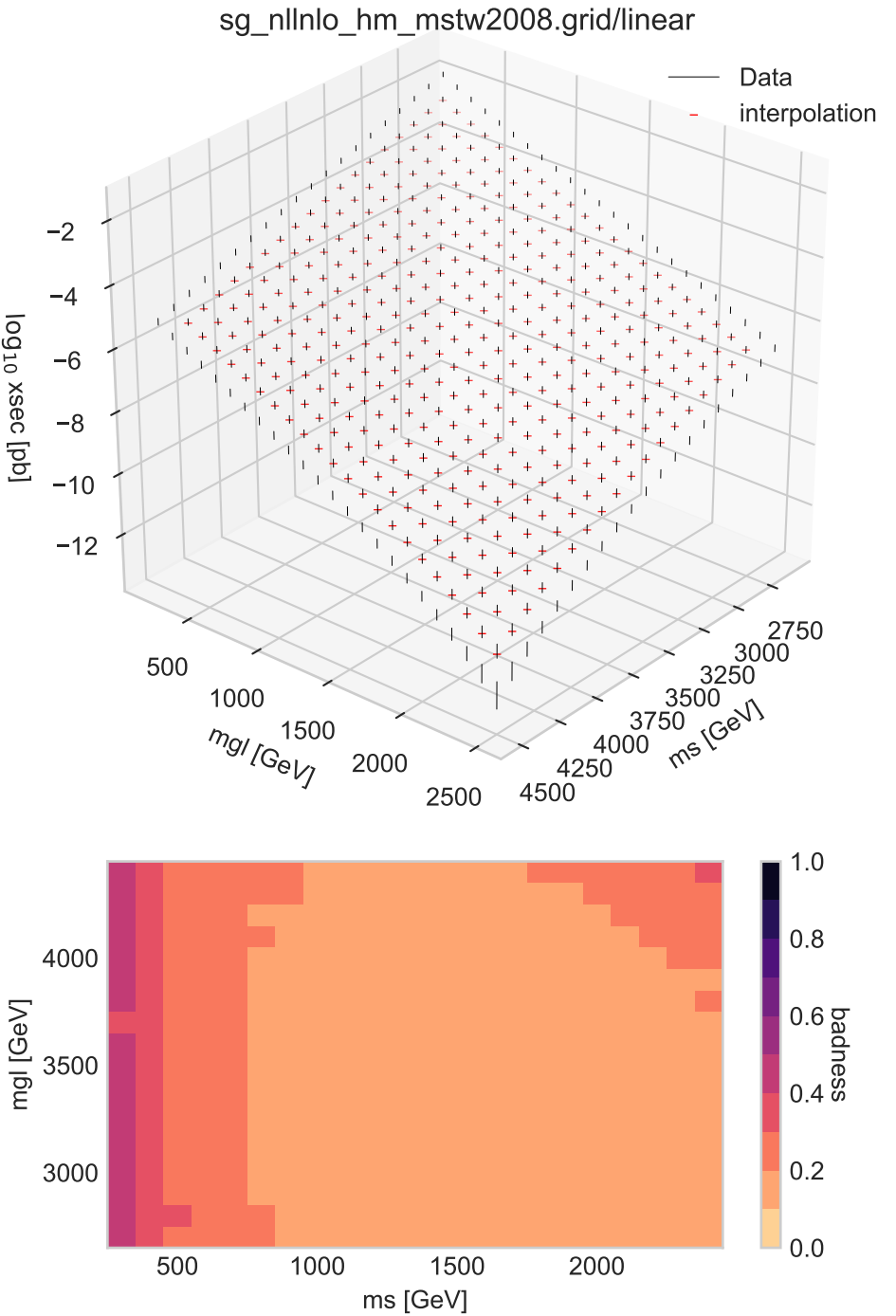

sg_nllnlo_hm_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
−2
−3
−4
−5
−6
−7
−8
200
400
600
800
1000
1200
1400
mgl [GeV]
2200
2400
2600
2800
3000
3200
3400
ms [GeV]
mgl [GeV]
3400
3200
3000
2800
2600
2400
2200
400
600
800
1000
1200
1400
ms [GeV]
1.0
0.8
0.6
0.4
0.2
0.0
badness

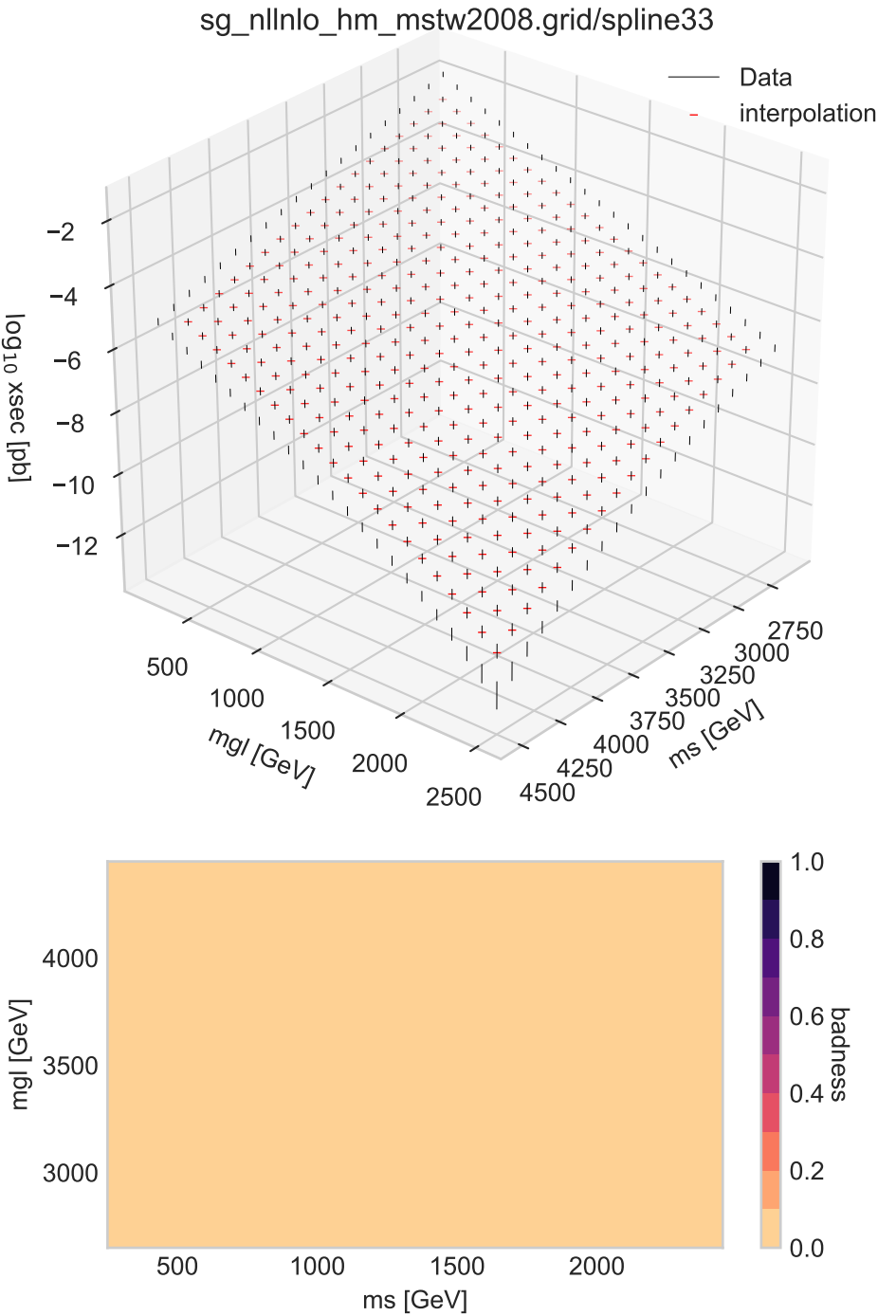

sg_nllnlo_hm_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
−2
−3
−4
−5
−6
−7
−8
200
400
600
800
1000
1200
1400
mgl [GeV]
2200
2400
2600
2800
3000
3200
3400
ms [GeV]

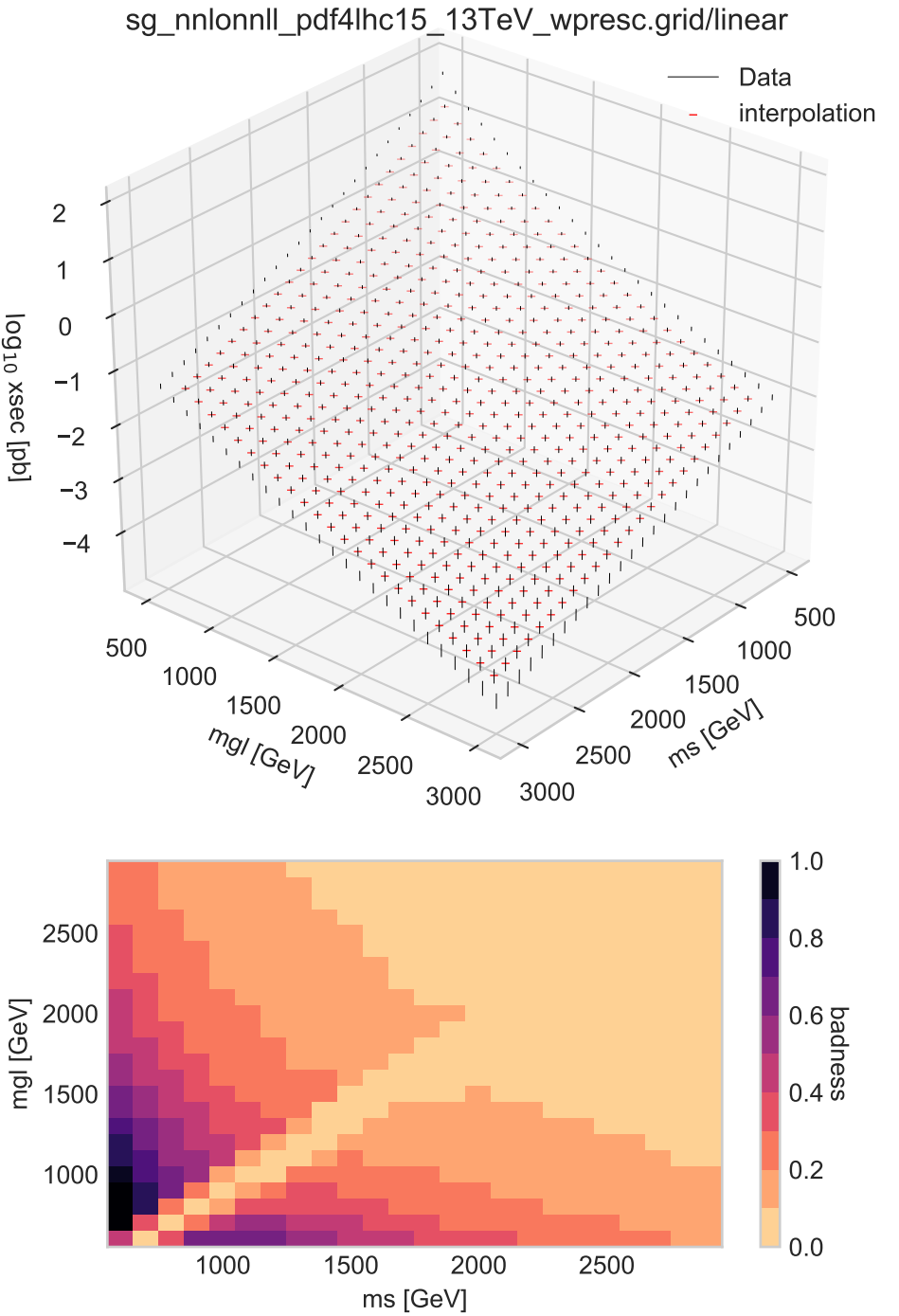

mgl [GeV]
3400
3200
3000
2800
2600
2400
2200
400
600
800
1000
1200
1400
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

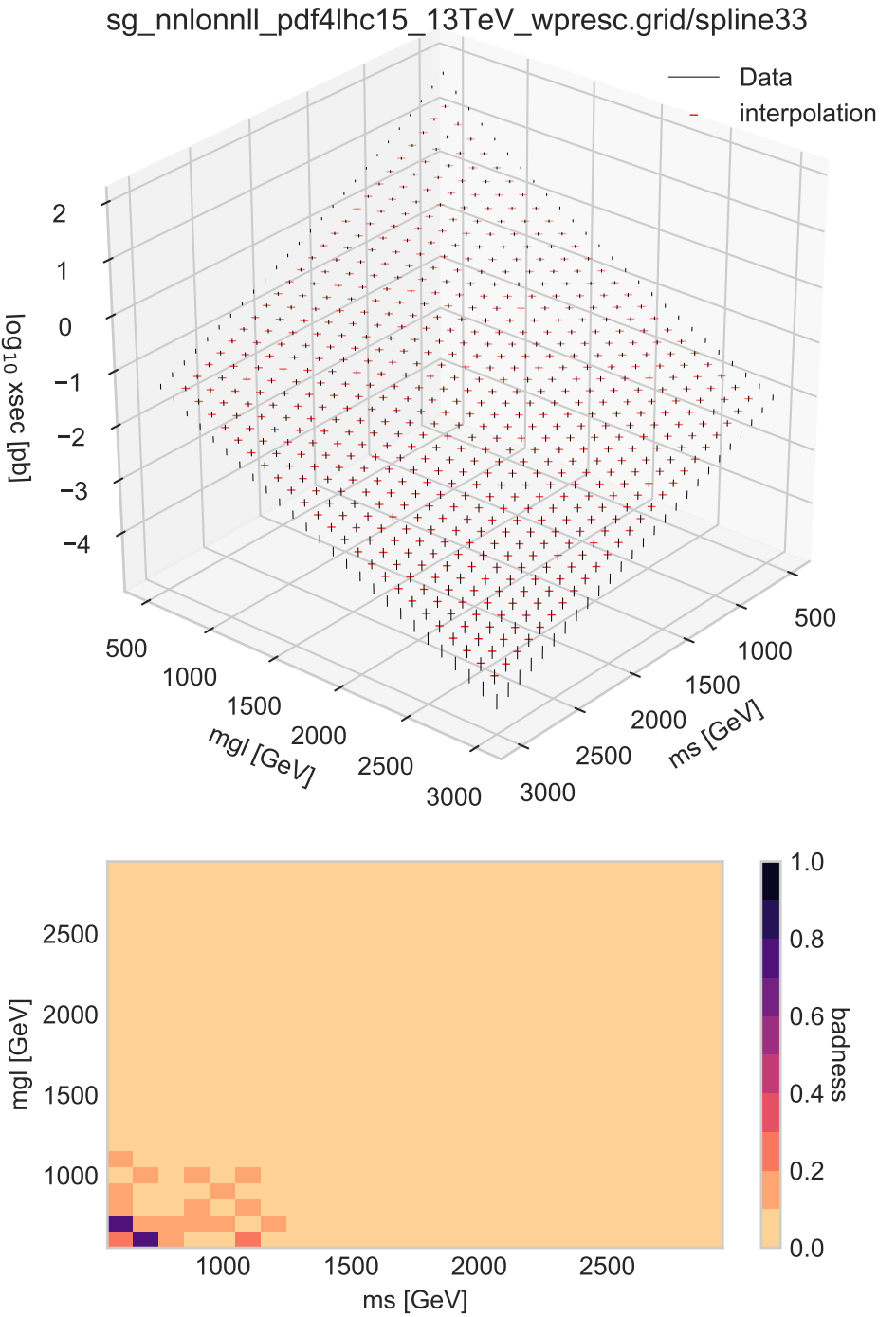

sg_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
500
1000
1500
2000
2500
ms [GeV]
500
1000
1500
2000
2500
mgl [GeV]
2000
1500
1000
500
ms [GeV]
500
1000
1500
2000
badness
1.0
0.8
0.6
0.4
0.2
0.0

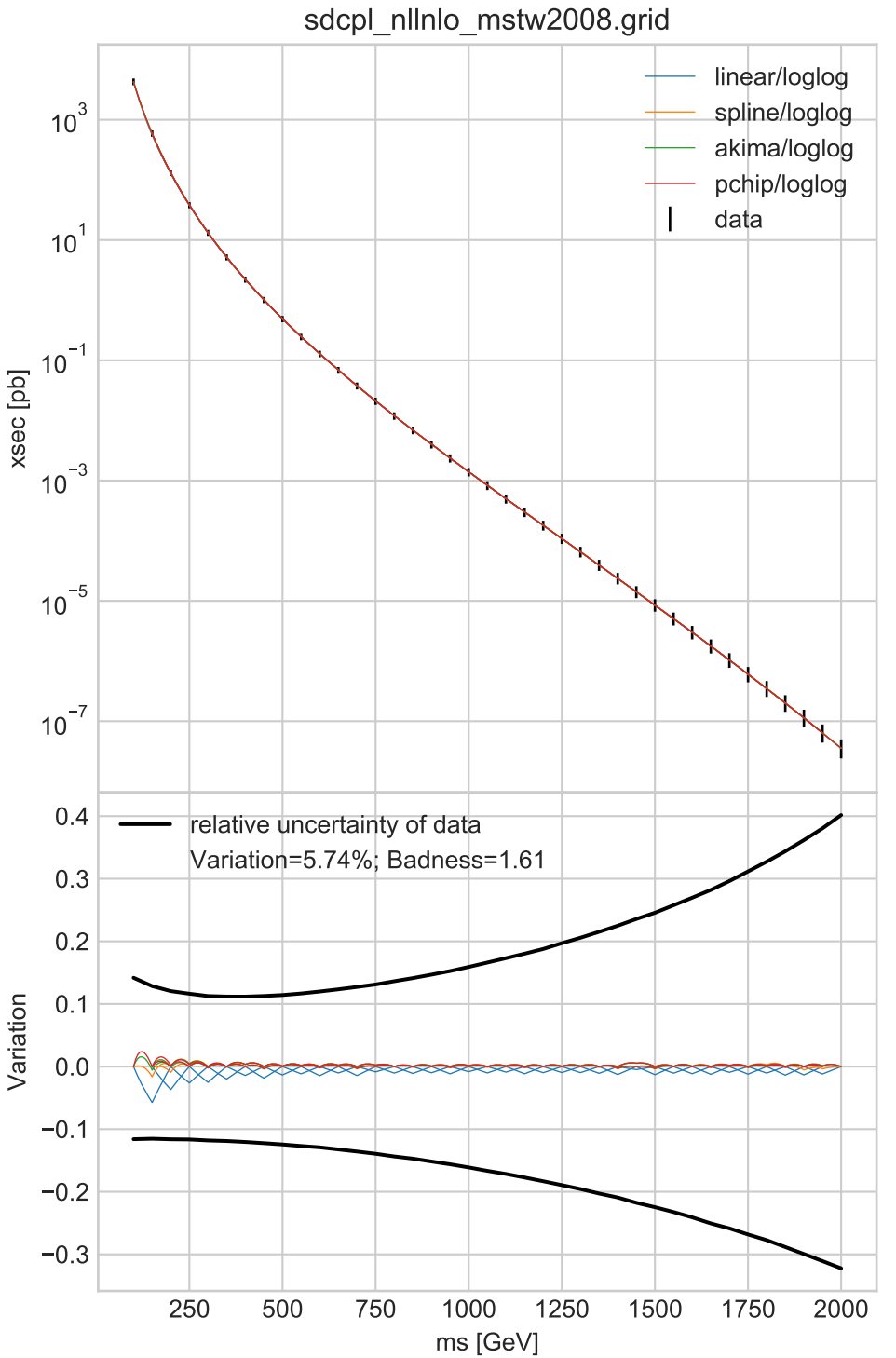

sg_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
500
1000
1500
2000
2500
ms [GeV]
500
1000
1500
2000
2500
mgl [GeV]
2000
1500
1000
500
ms [GeV]
500
1000
1500
2000
badness
1.0
0.8
0.6
0.4
0.2
0.0

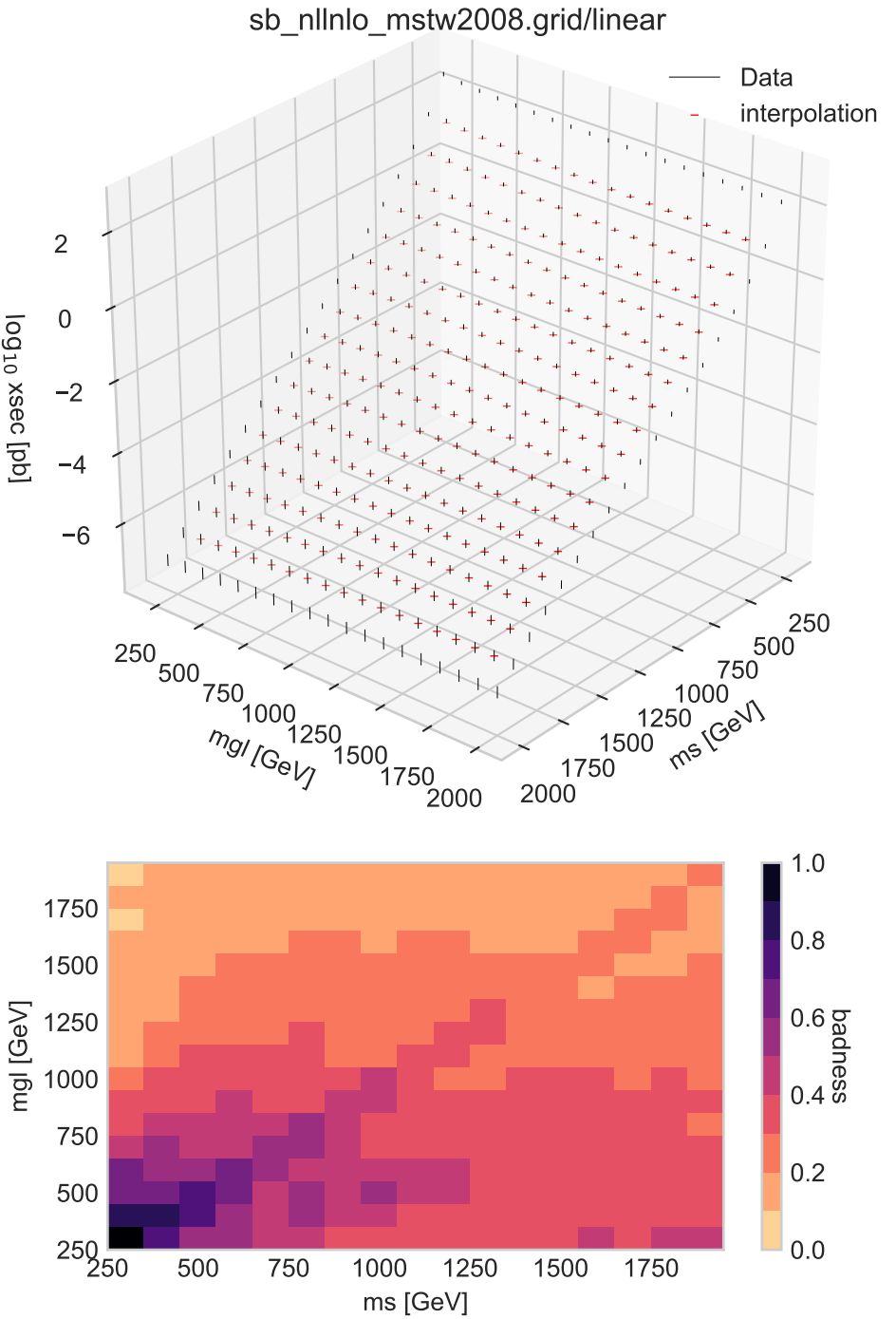

sg_nllnlo_hm_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
−2
−4
−6
−8
−10
−12
500
1000
1500
2000
2500
mgl [GeV]
2750
3000
3250
3500
3750
4000
4250
4500
ms [GeV]
mgl [GeV]
4000
3500
3000
500
1000
1500
2000
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

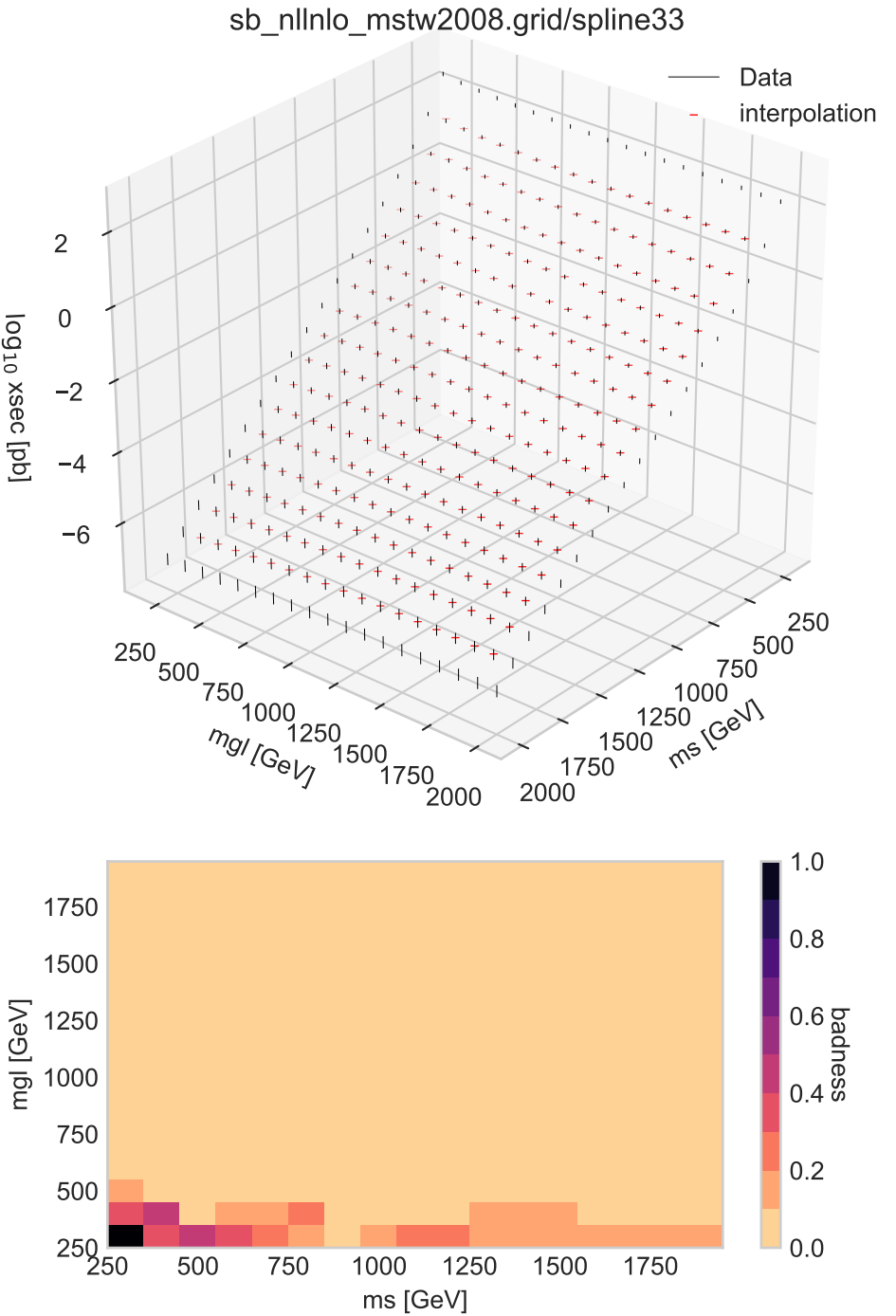

sg_nllnlo_hm_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
−2
−4
−6
−8
−10
−12
500
1000
1500
2000
2500
mgl [GeV]
2750
3000
3250
3500
3750
4000
4250
4500
ms [GeV]
mgl [GeV]
4000
3500
3000
500
1000
1500
2000
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

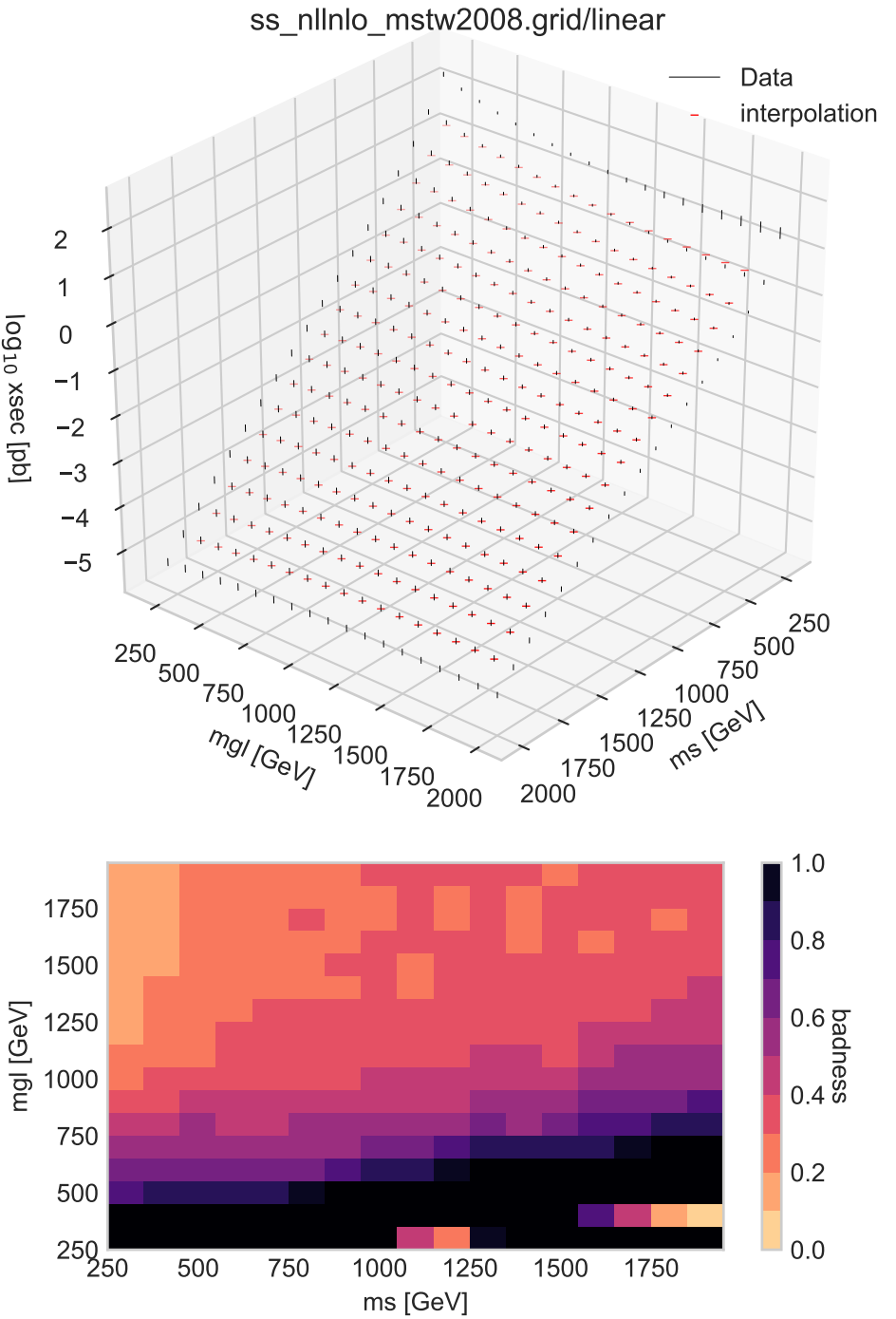

sg_nnlonnll_pdf4lhc15_13TeV_wpresc.grid/linear
Data
interpolation
log10 xsec [pb]
2
1
0
−1
−2
−3
−4
500
1000
1500
2000
2500
3000
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

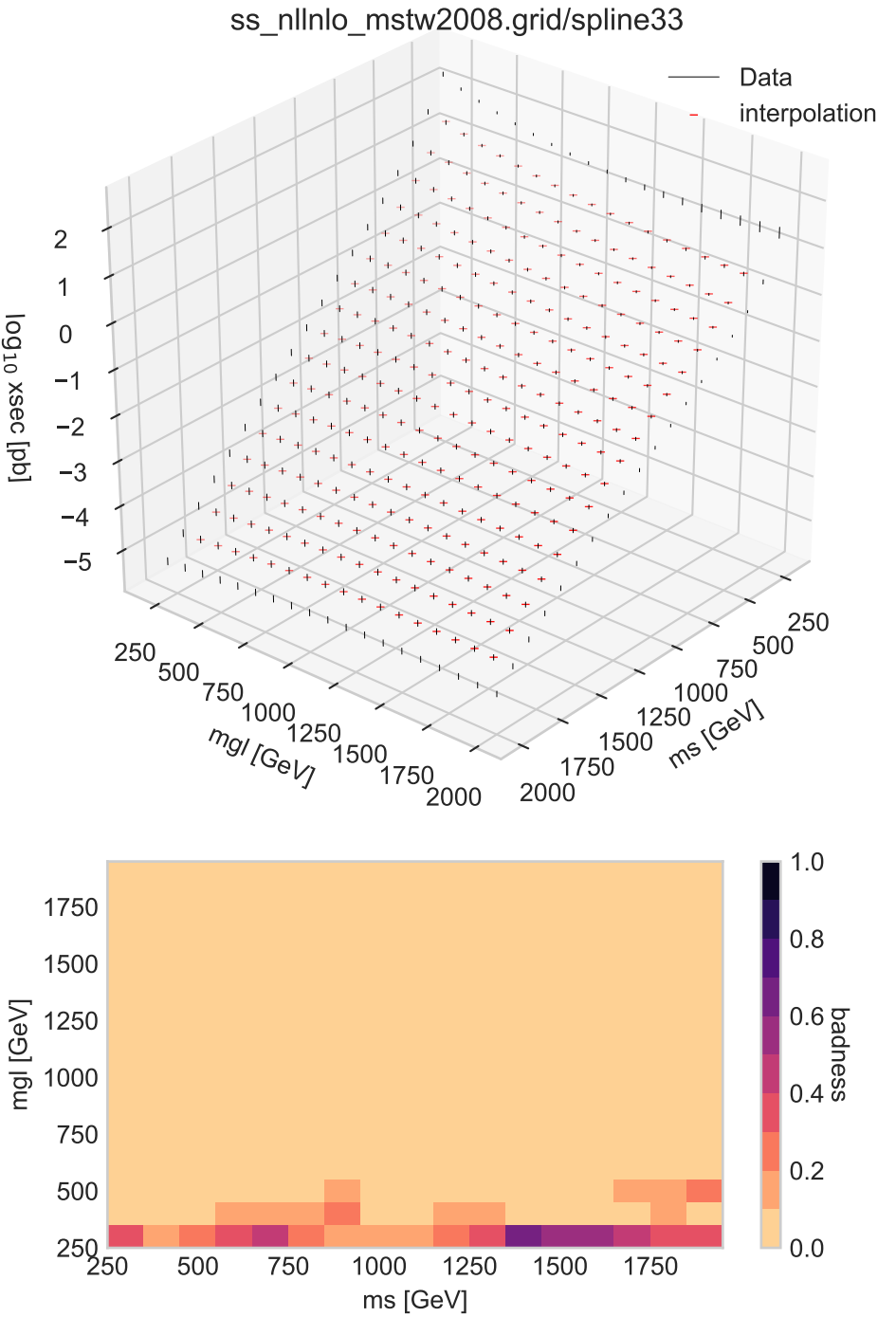

sg_nnlonnll_pdf4lhc15_13TeV_wpresc.grid/spline33
Data
interpolation
log10 xsec [pb]
2
1
0
−1
−2
−3
−4
500
1000
1500
2000
2500
3000
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

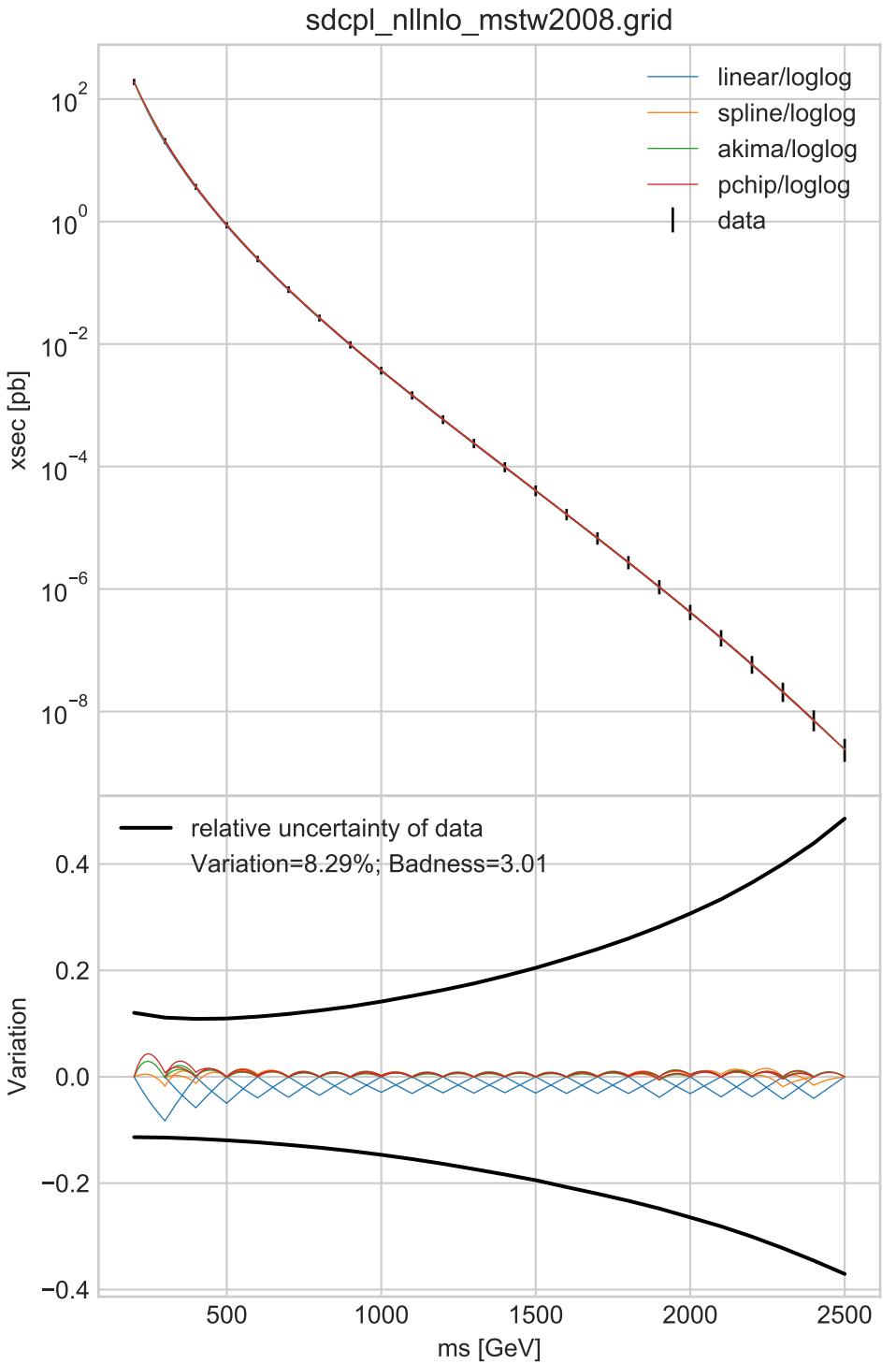

sdcpl_nllnlo_mstw2008.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
10^{3}
10^{1}
10^{-1}
10^{-3}
10^{-5}
10^{-7}
relative uncertainty of data
Variation=5.74%; Badness=1.61
Variation
0.4
0.3
0.2
0.1
0.0
−0.1
−0.2
−0.3
250
500
750
1000
1250
1500
1750
2000
ms [GeV]

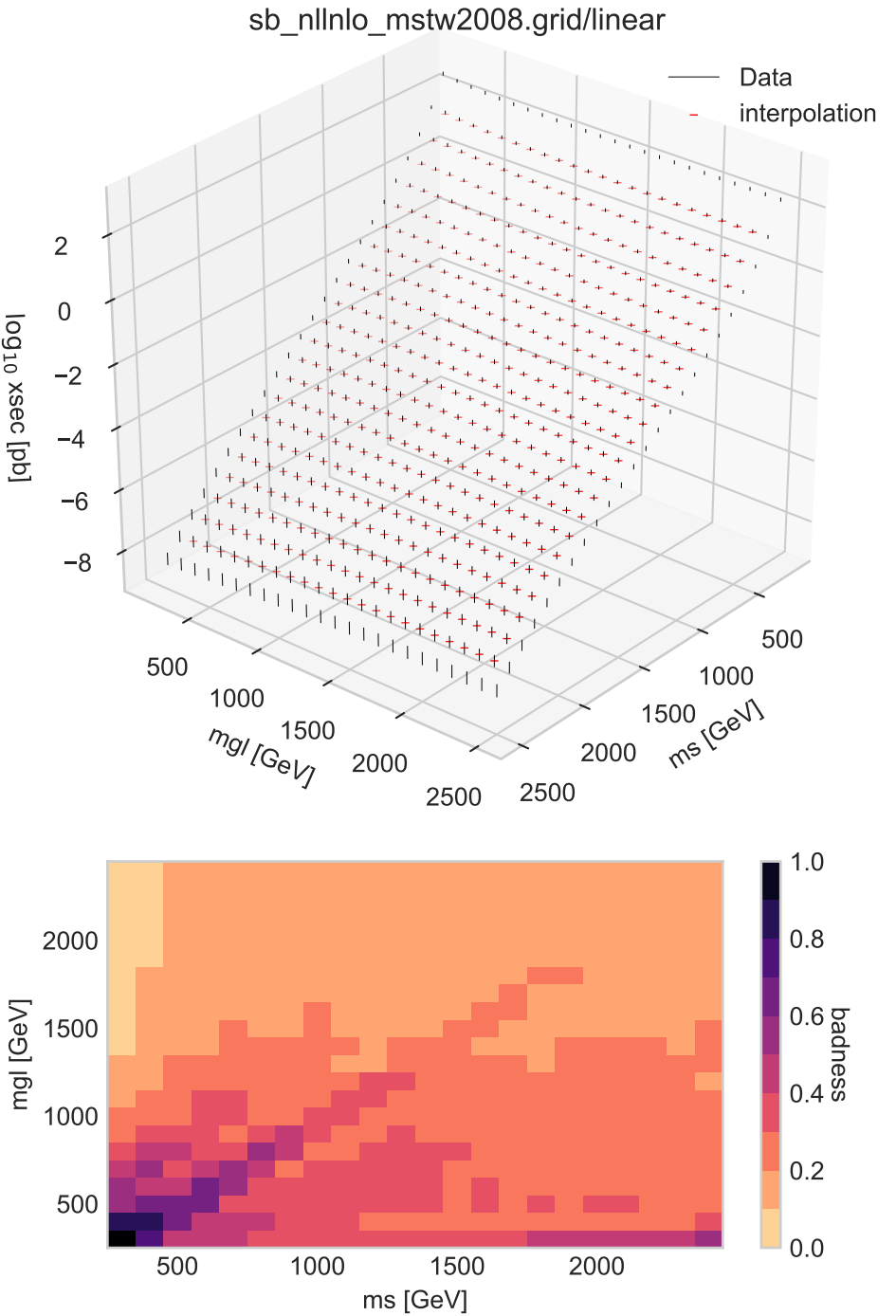

sb_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
badness
0.0
0.2
0.4
0.6
0.8
1.0

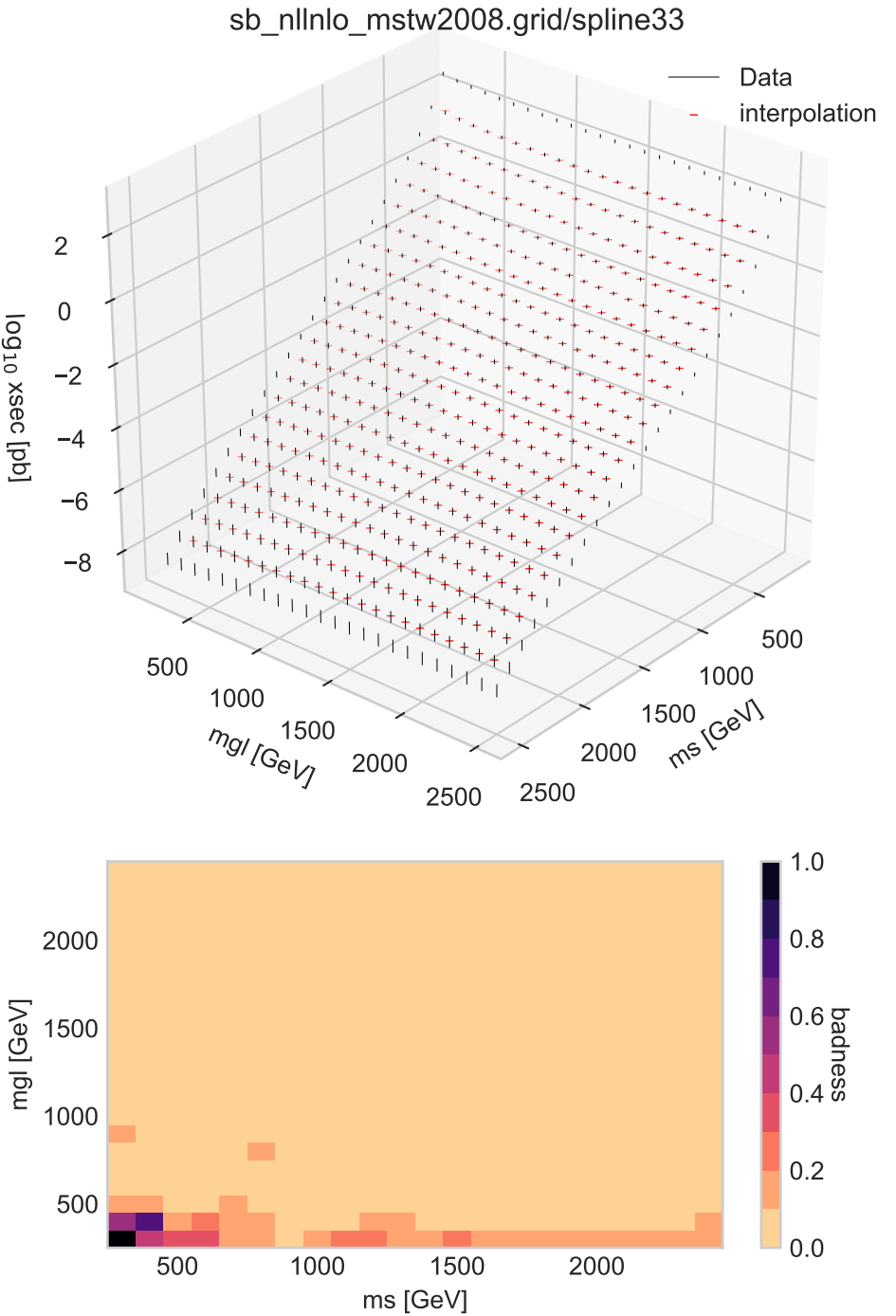

sb_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
250
500
750
1000
1250
1500
1750
2000
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
badness
0.0
0.2
0.4
0.6
0.8
1.0

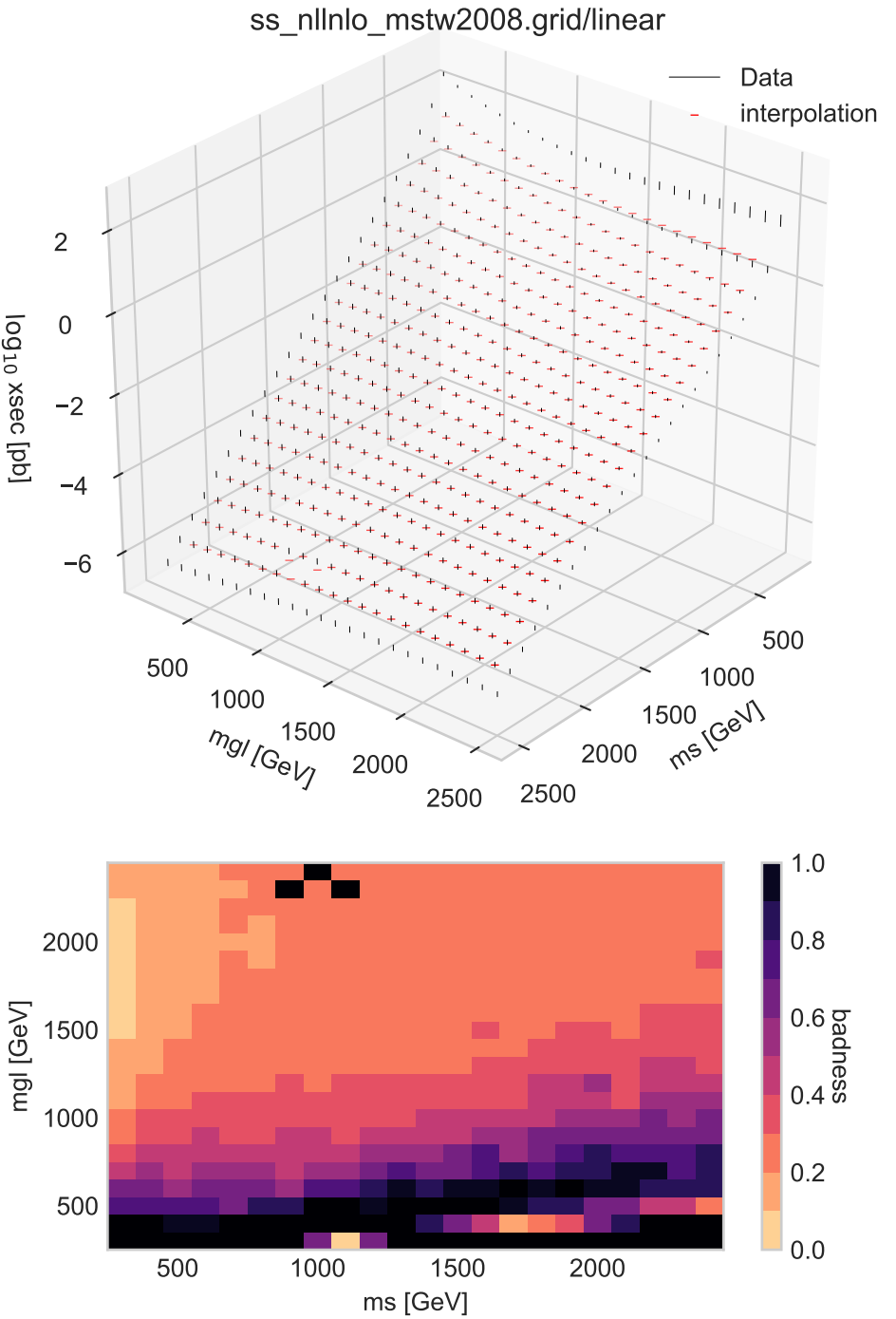

ss_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
1
0
−1
−2
−3
−4
−5
mgl [GeV]
250
500
750
1000
1250
1500
1750
2000
ms [GeV]
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
250
500
750
1000
1250
1500
1750
ms [GeV]
250
500
750
1000
1250
1500
1750
badness
0.0
0.2
0.4
0.6
0.8
1.0

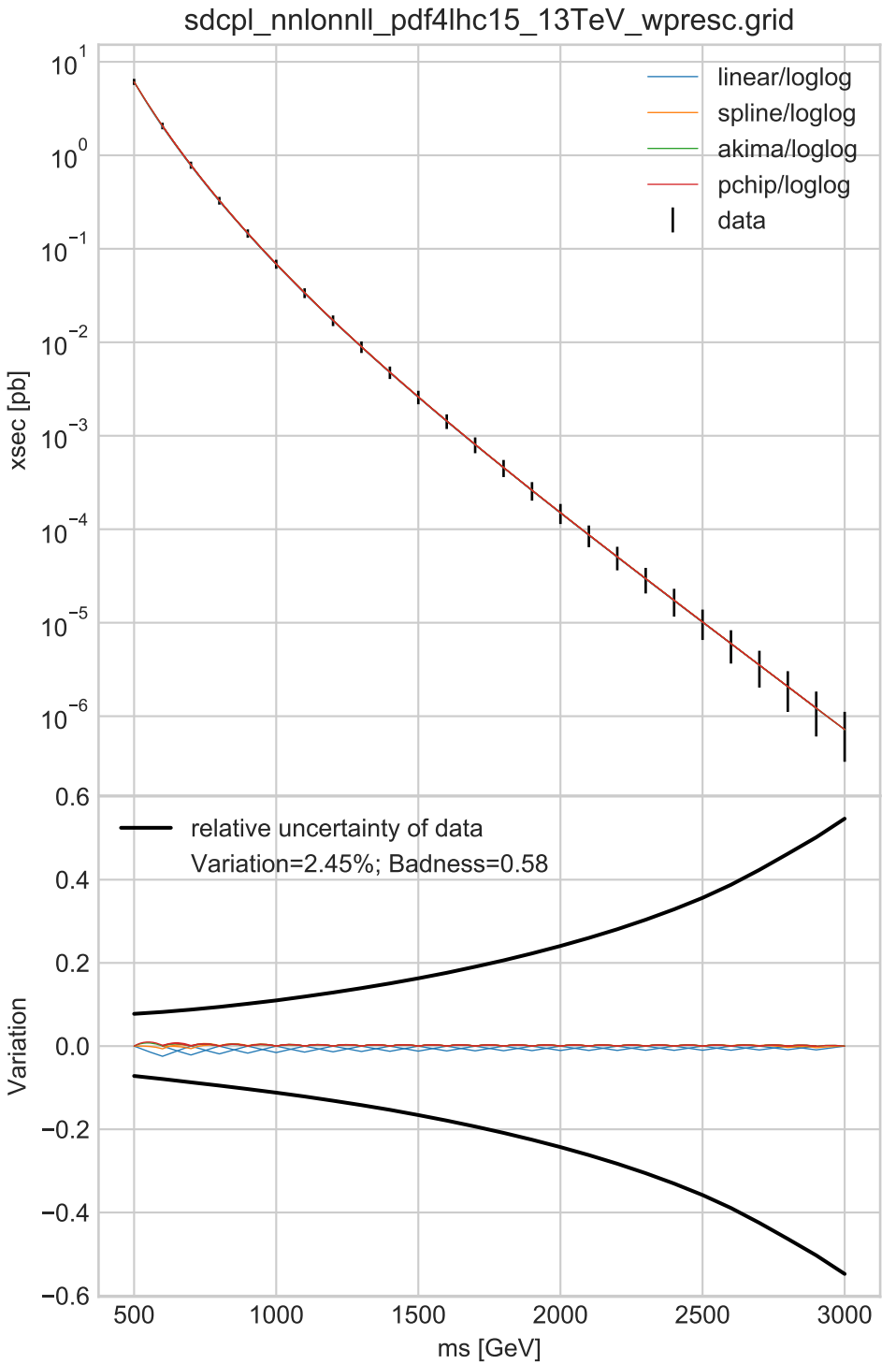

ss_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
1
0
−1
−2
−3
−4
−5
250
500
750
1000
1250
1500
1750
2000
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

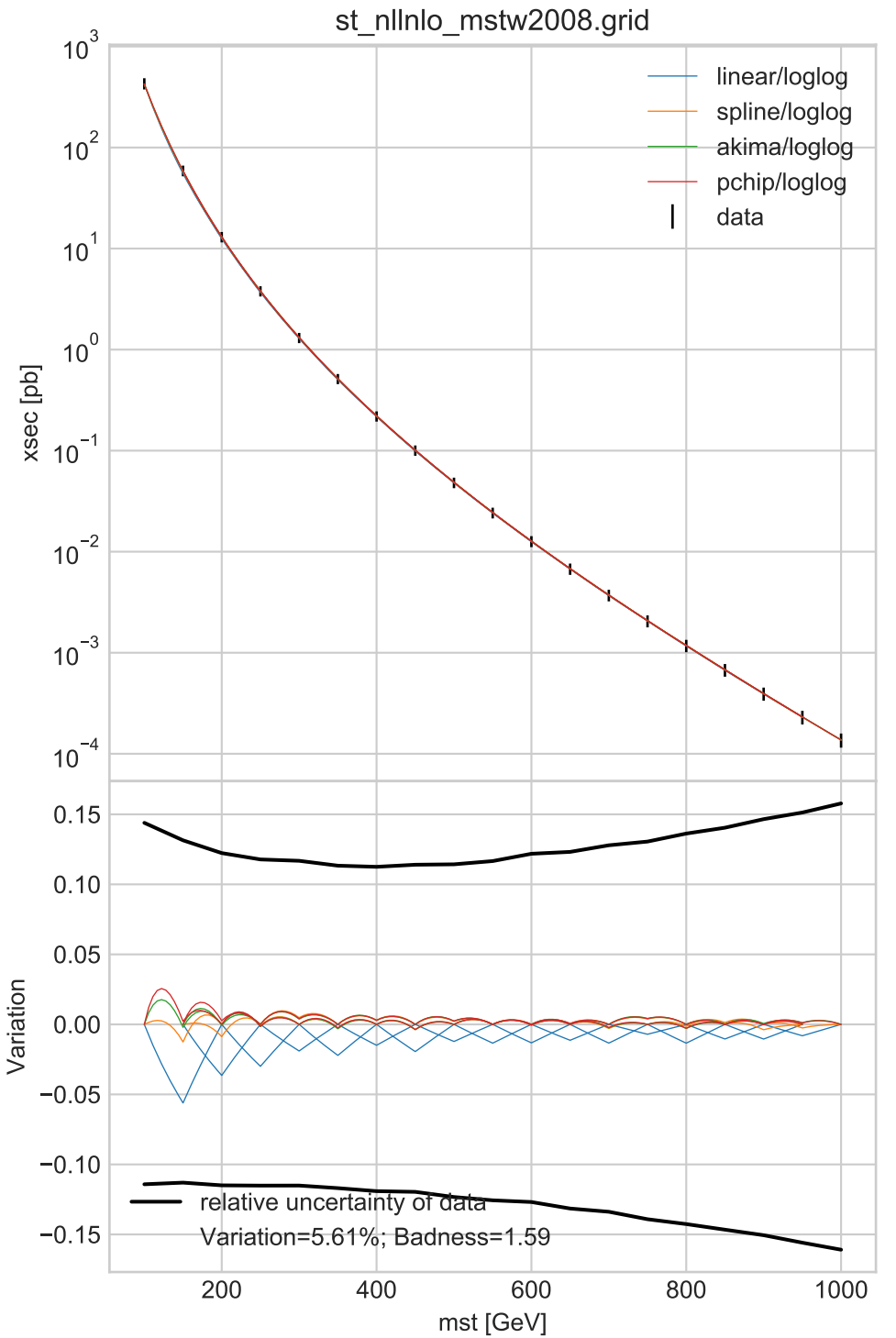

sdcpl_nllnlo_mstw2008.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
relative uncertainty of data
Variation=8.29%; Badness=3.01
Variation
ms [GeV]

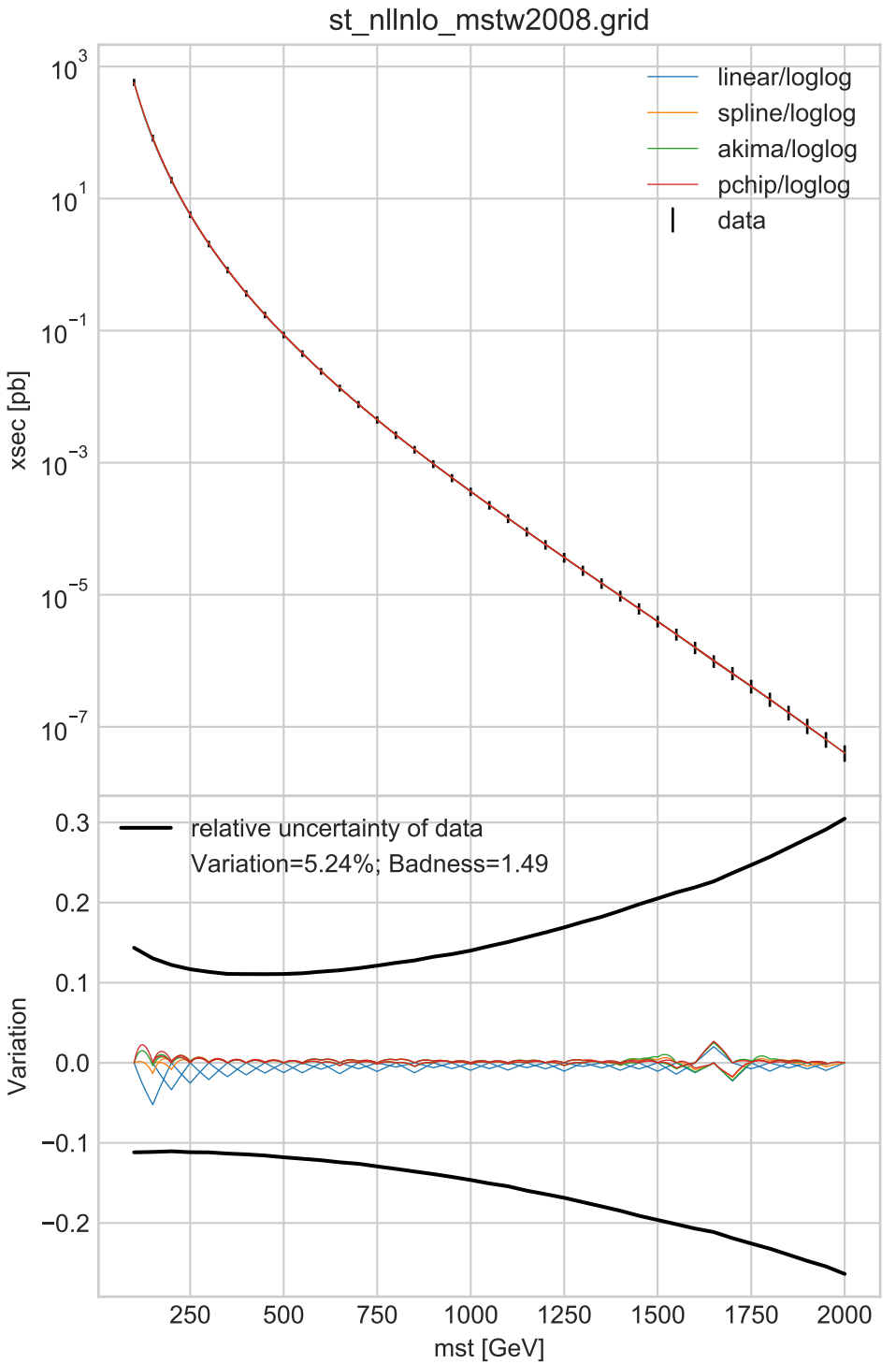

sb_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
500
1000
1500
2000
2500
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

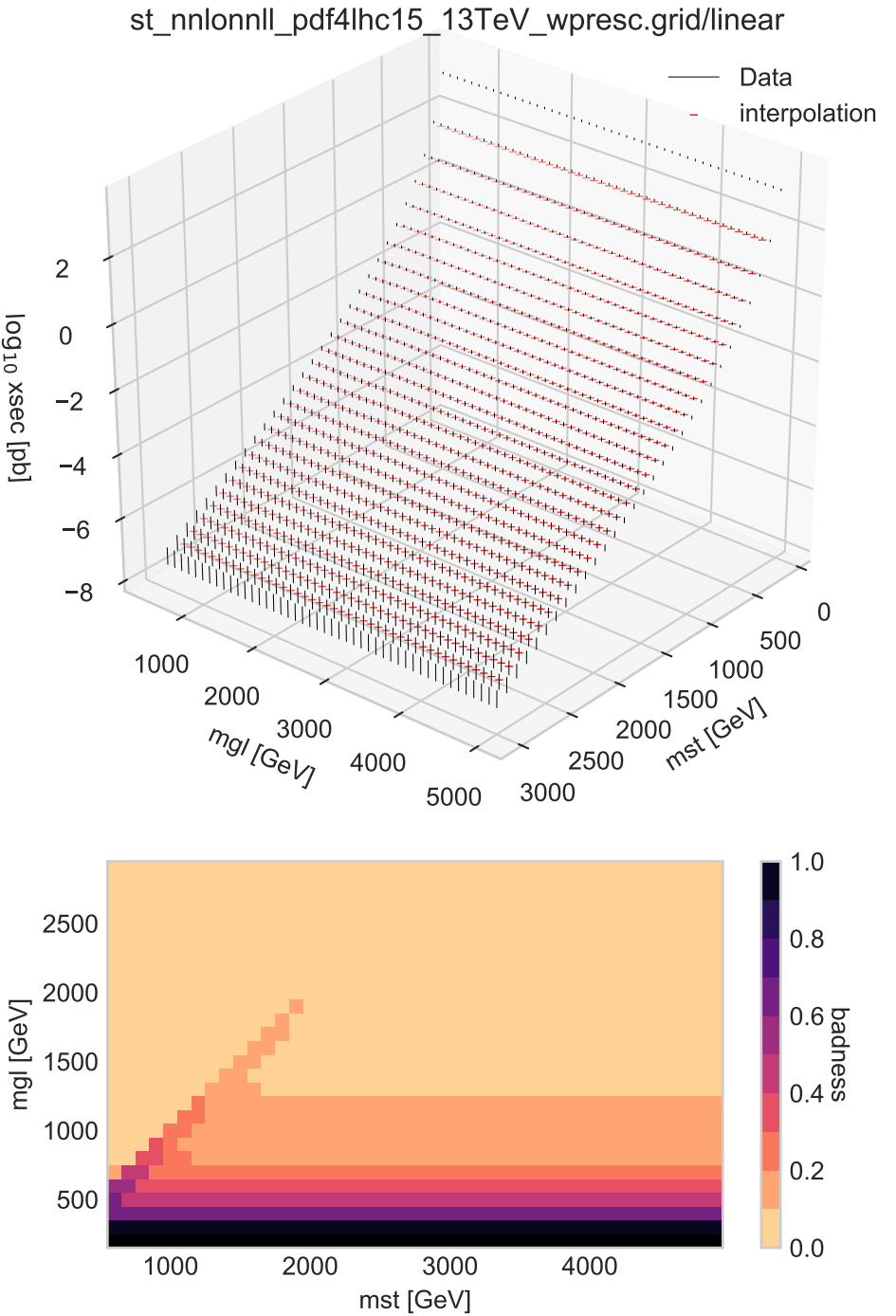

sb_nllnlo_mstw2008.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
500
1000
1500
2000
2500
mgl [GeV]
ms [GeV]
mgl [GeV]
ms [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

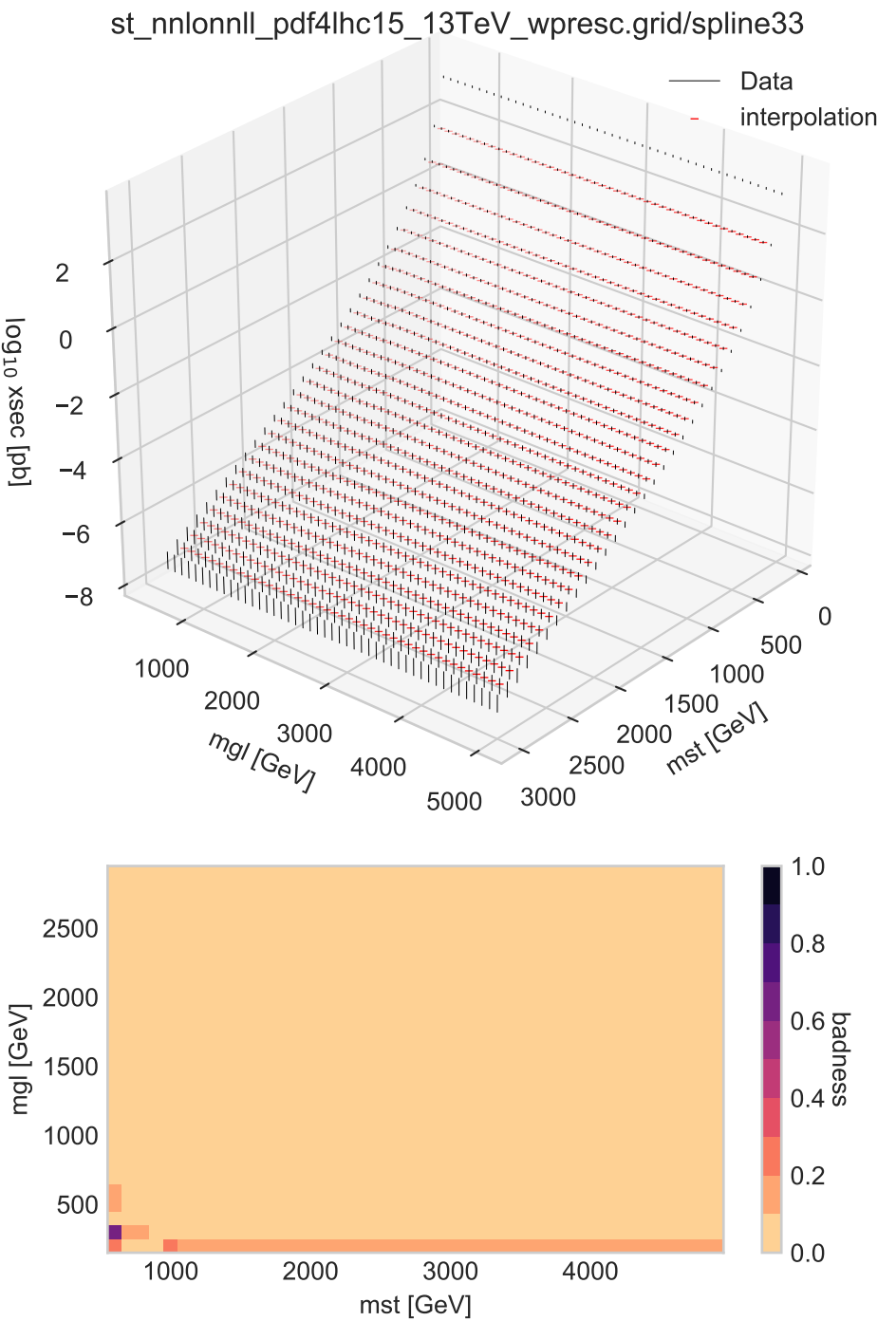

ss_nllnlo_mstw2008.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
mgl [GeV]
500
1000
1500
2000
2500
ms [GeV]
500
1000
1500
2000
2500
mgl [GeV]
2000
1500
1000
500
ms [GeV]
500
1000
1500
2000
badness
1.0
0.8
0.6
0.4
0.2
0.0

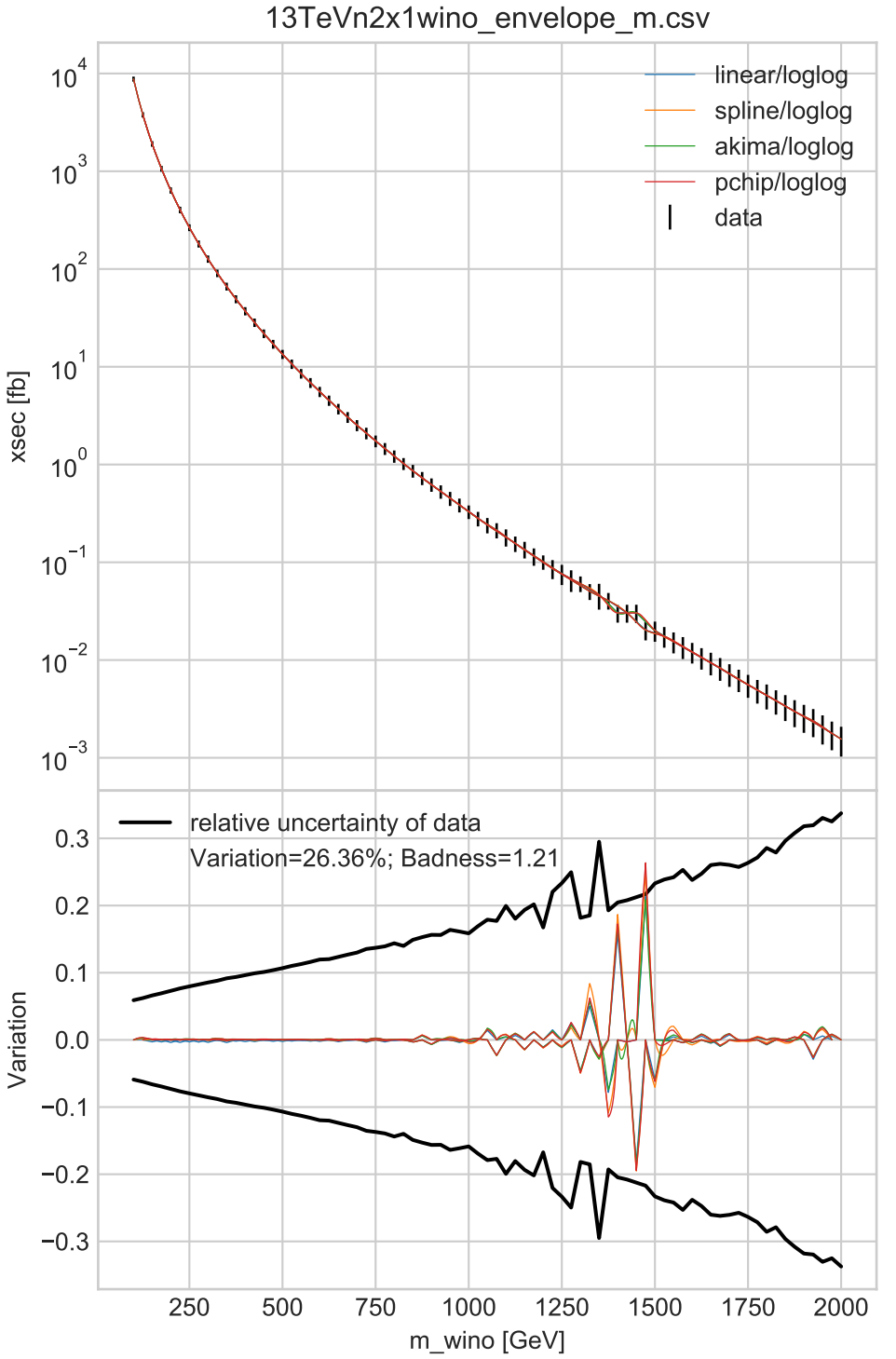

sdcpl_nnlonnll_pdf4lhc15_13TeV_wpresc.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
relative uncertainty of data
Variation=2.45%; Badness=0.58
Variation
ms [GeV]

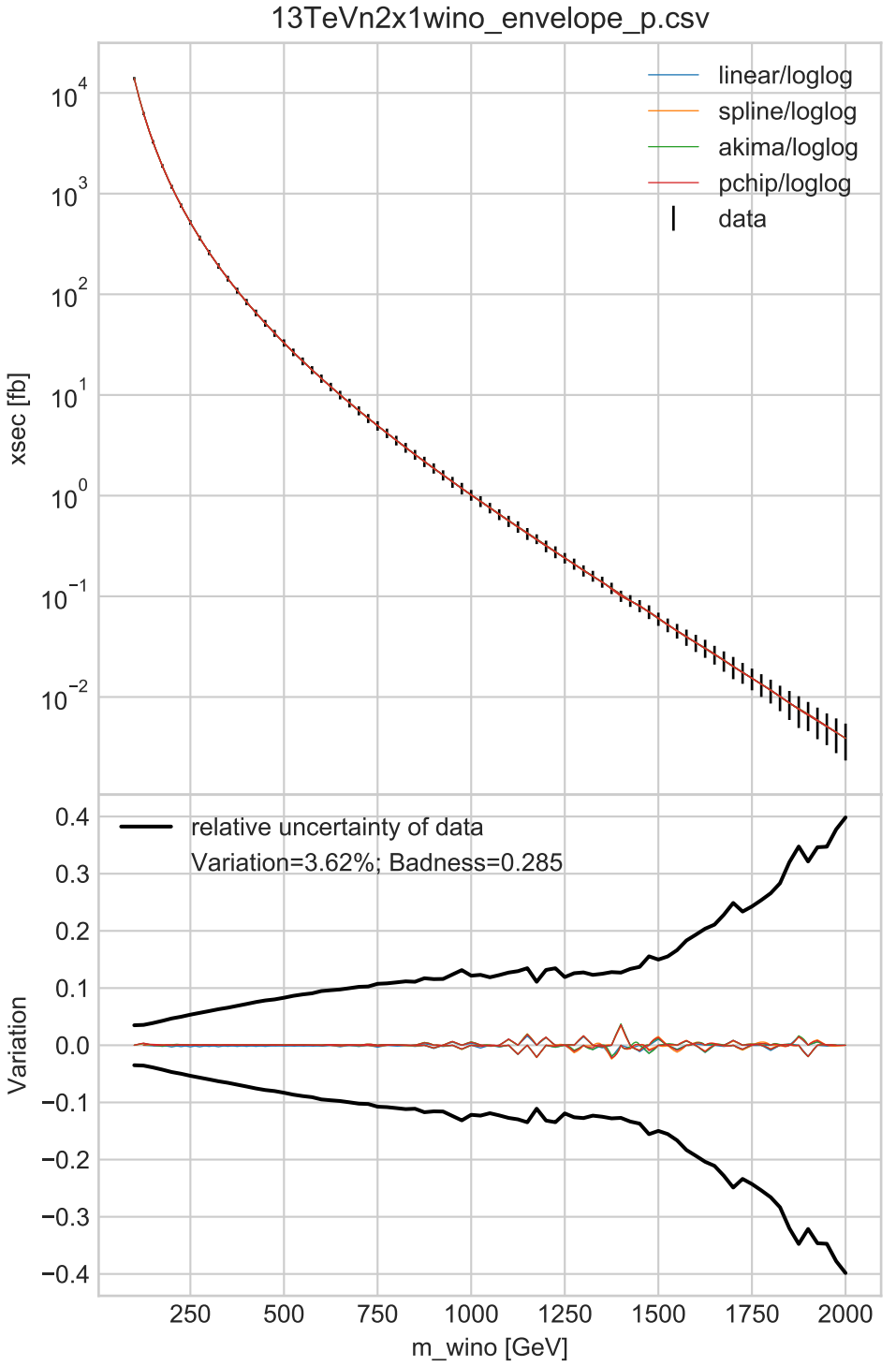

st_nllnlo_mstw2008.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
Variation
relative uncertainty of data
Variation=5.61%; Badness=1.59
mst [GeV]

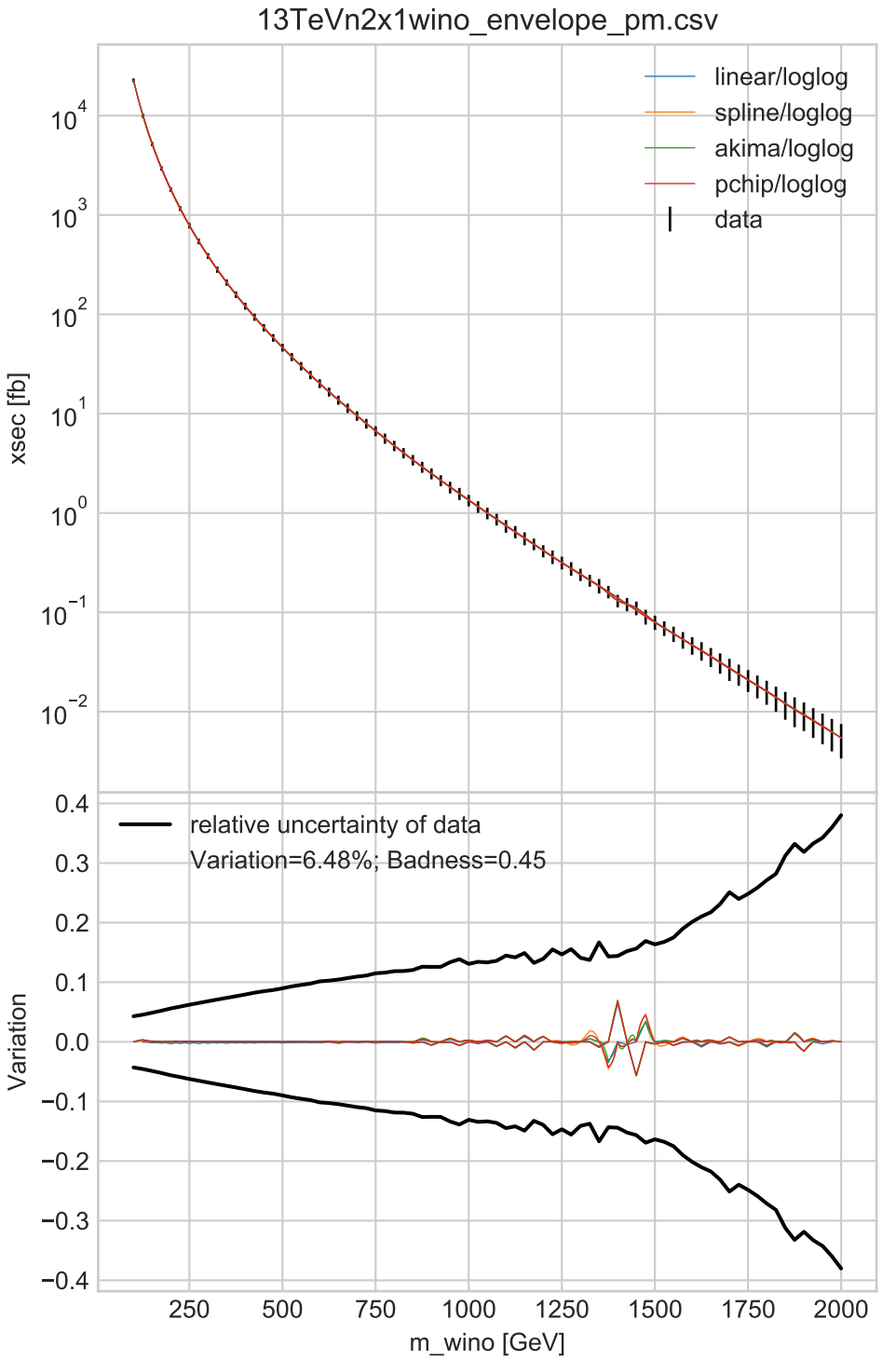

st_nllnlo_mstw2008.grid
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [pb]
relative uncertainty of data
Variation=5.24%; Badness=1.49
Variation
mst [GeV]

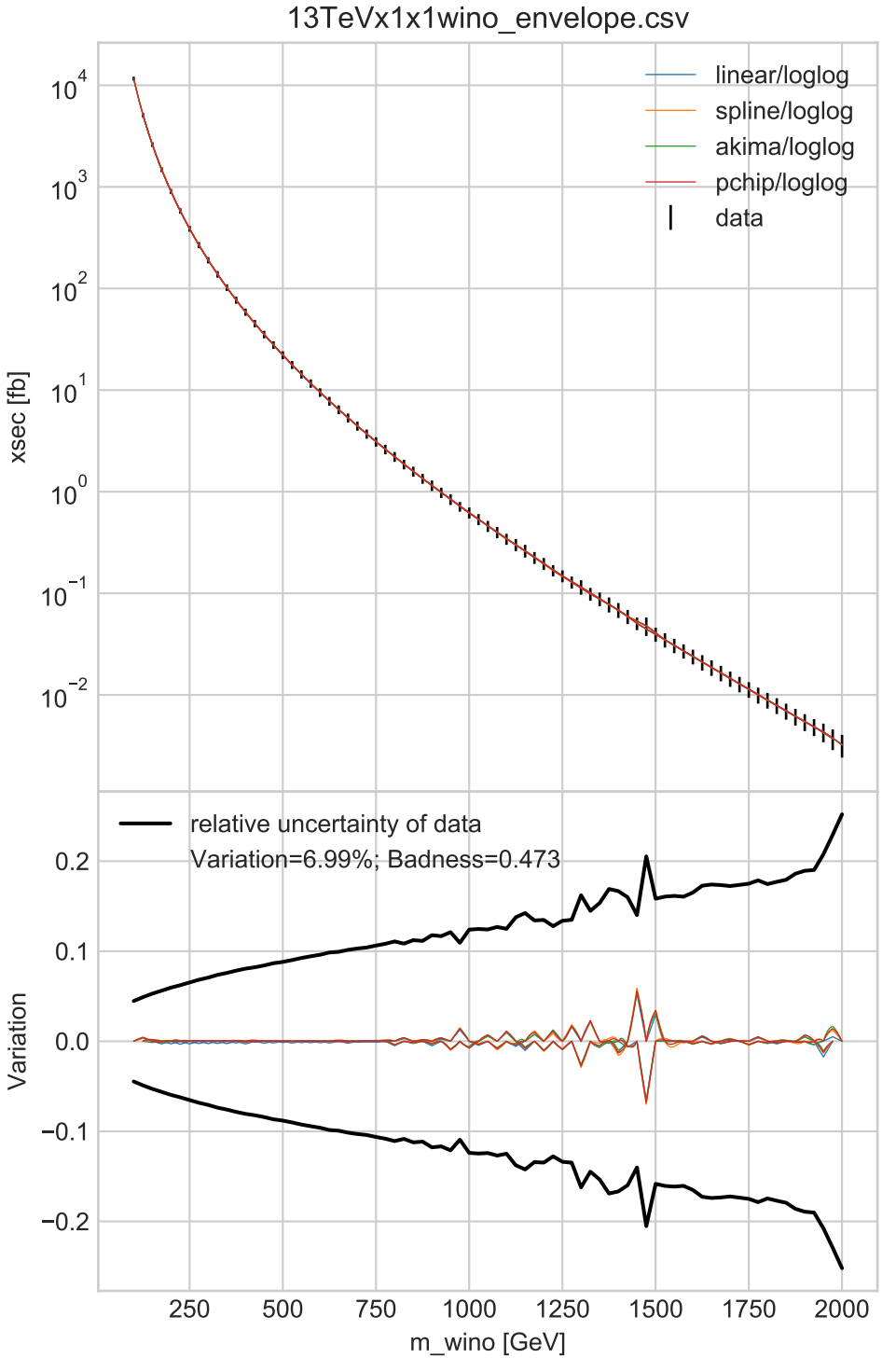

st_nnlonnll_pdf4lhc15_13TeV_wpresc.grid/linear
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
1000
2000
3000
4000
5000
mgl [GeV]
0
500
1000
1500
2000
2500
3000
mst [GeV]
mgl [GeV]
2500
2000
1500
1000
500
1000
2000
3000
4000
mst [GeV]
badness
1.0
0.8
0.6
0.4
0.2
0.0

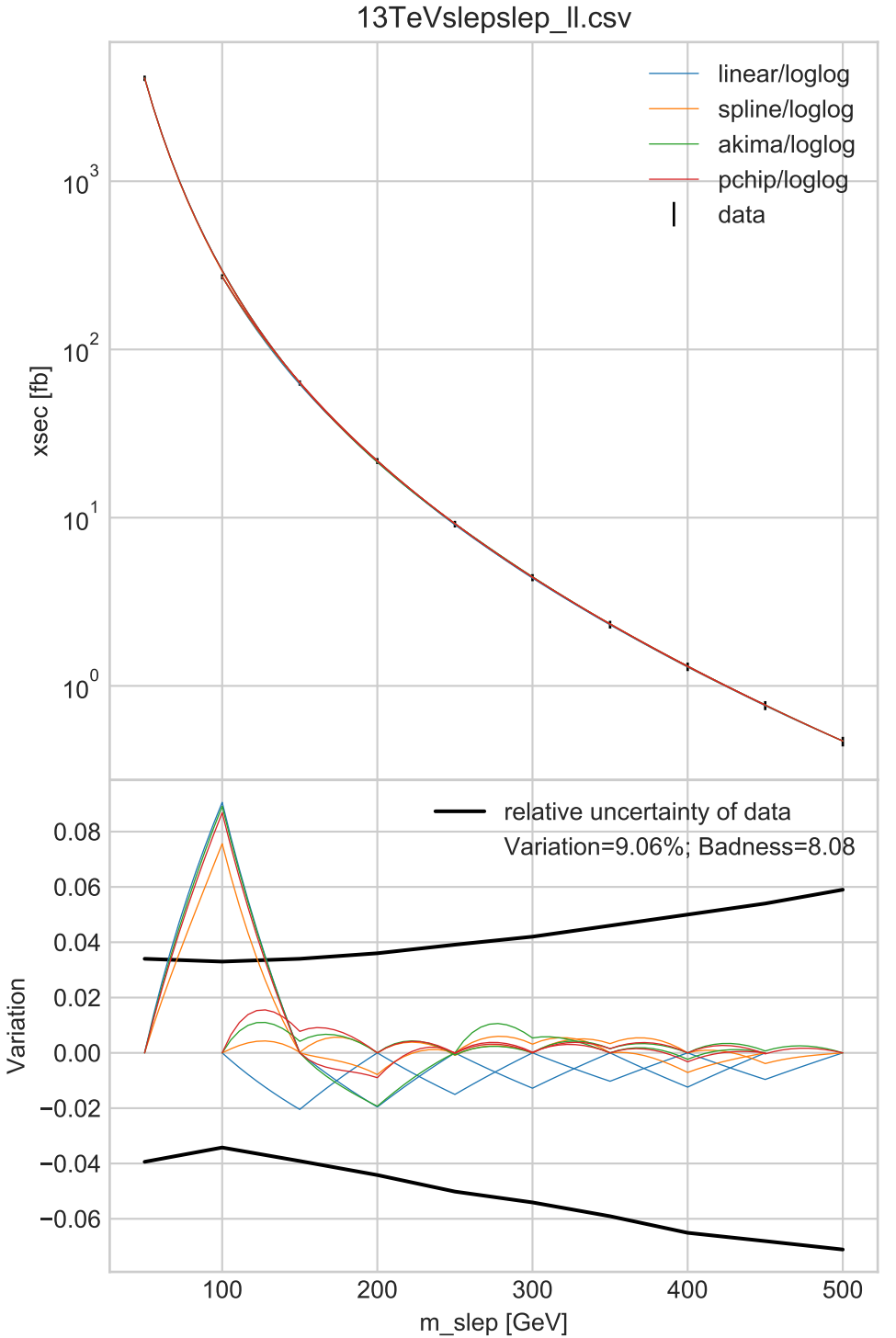

st_nnlonnll_pdf4lhc15_13TeV_wpresc.grid/spline33
Data
interpolation
log10 xsec [pb]
2
0
−2
−4
−6
−8
mgl [GeV]
1000
2000
3000
4000
5000
mst [GeV]
0
500
1000
1500
2000
2500
3000
mgl [GeV]
2500
2000
1500
1000
500
mst [GeV]
1000
2000
3000
4000
badness
1.0
0.8
0.6
0.4
0.2
0.0

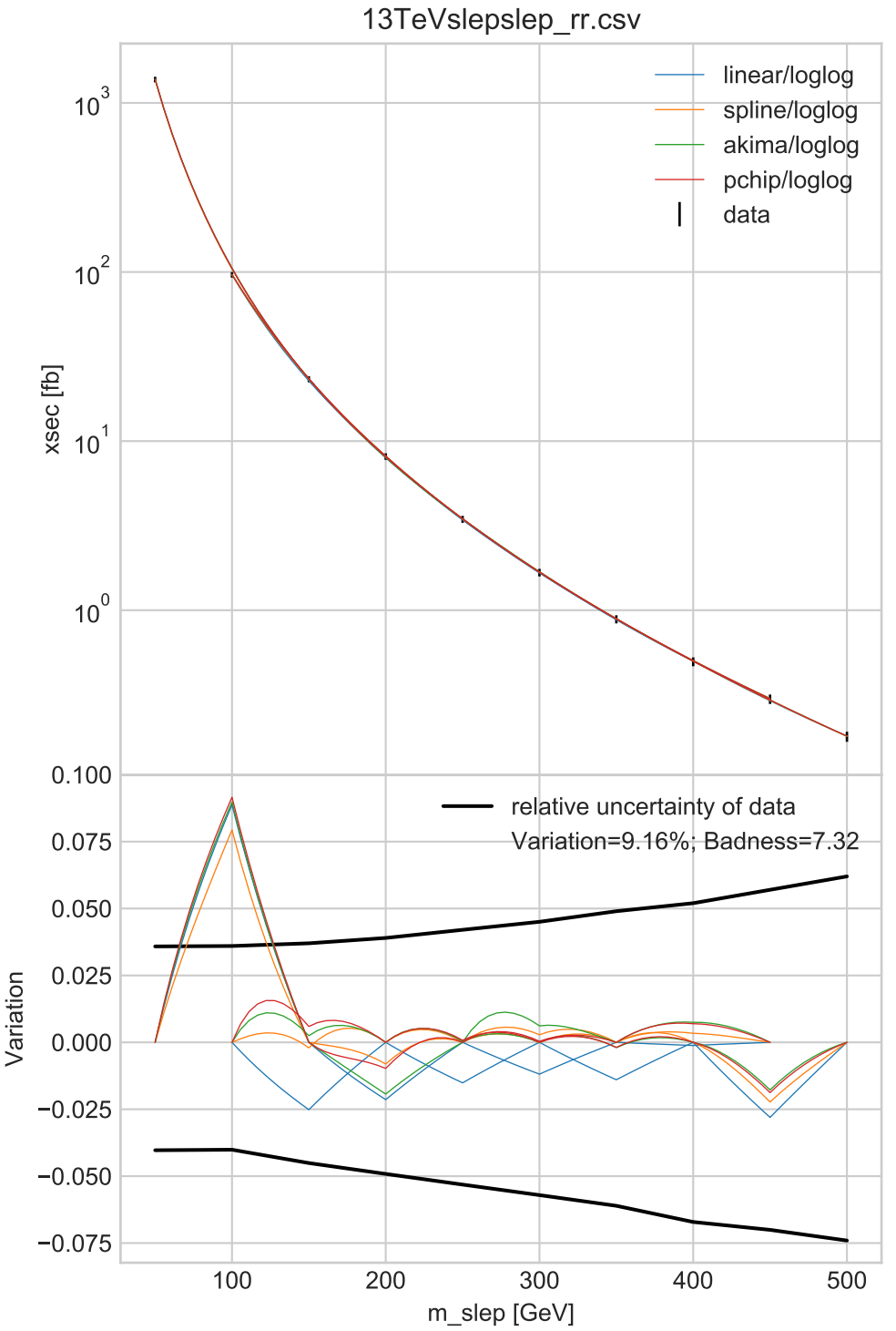

13TeVn2x1wino_envelope_m.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
relative uncertainty of data
Variation=26.36%; Badness=1.21
Variation
m_wino [GeV]

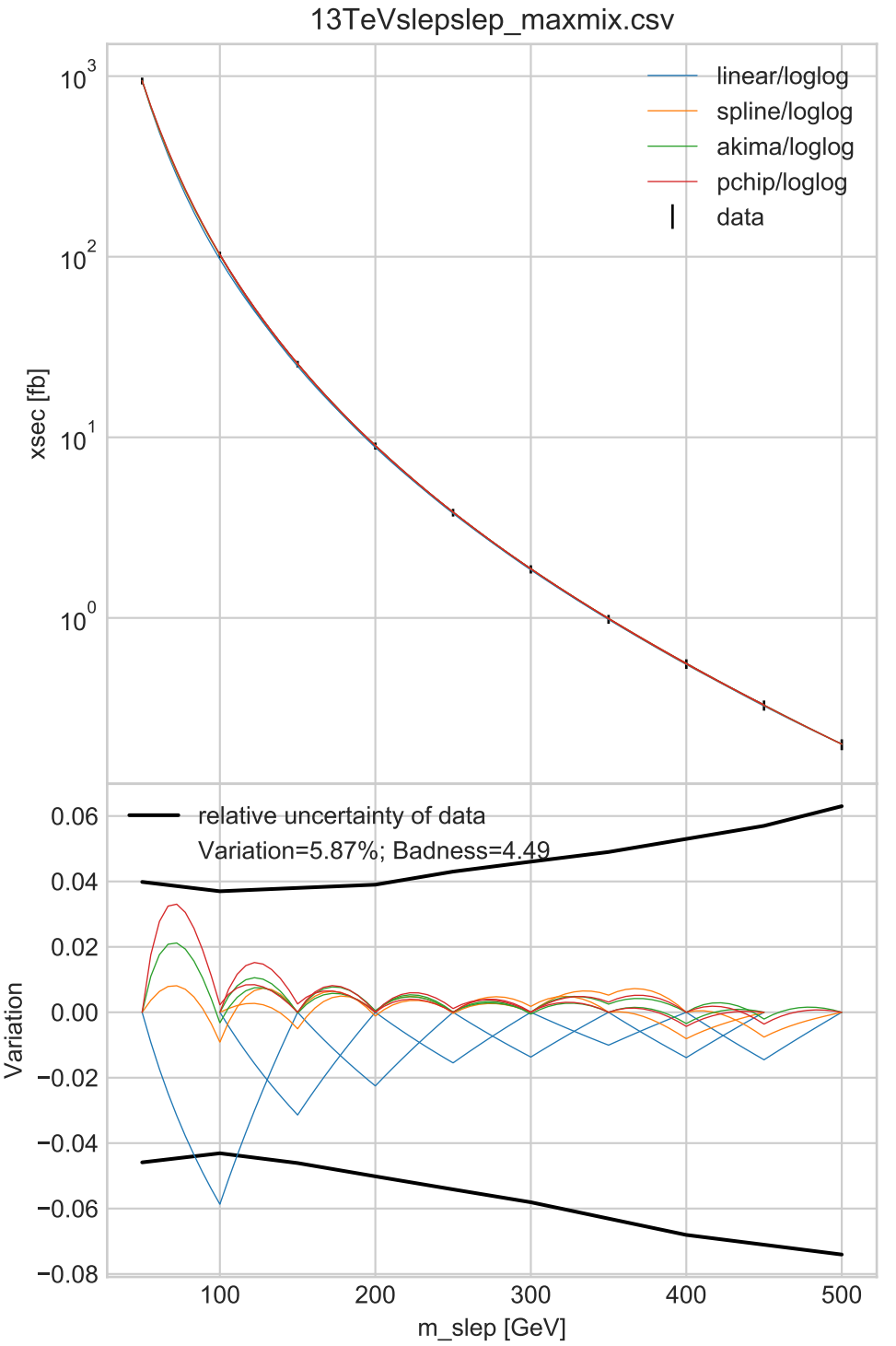

13TeVn2x1wino_envelope_p.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
relative uncertainty of data
Variation=3.62%; Badness=0.285
Variation
m_wino [GeV]


13TeVn2x1wino_envelope_pm.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
relative uncertainty of data
Variation=6.48%; Badness=0.45
Variation
m_wino [GeV]


13TeVx1x1wino_envelope.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
relative uncertainty of data
Variation=6.99%; Badness=0.473
Variation
m_wino [GeV]


13TeVslepslep_ll.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
10^3
10^2
10^1
10^0
relative uncertainty of data
Variation=9.06%; Badness=8.08
Variation
0.08
0.06
0.04
0.02
0.00
−0.02
−0.04
−0.06
100
200
300
400
500
m_slep [GeV]


13TeVslepslep_rr.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
10^3
10^2
10^1
10^0
0.100
relative uncertainty of data
Variation=9.16%; Badness=7.32
0.075
0.050
0.025
0.000
−0.025
−0.050
−0.075
Variation
100
200
300
400
500
m_slep [GeV]


13TeVslepslep_maxmix.csv
linear/loglog
spline/loglog
akima/loglog
pchip/loglog
data
xsec [fb]
relative uncertainty of data
Variation=5.87%; Badness=4.49
Variation
m_slep [GeV]